

# TPS1HB08-Q1 40V、8mΩ 单通道智能高侧开关

## 1 特性

- 符合面向汽车应用的 AEC-Q100 标准
  - 温度等级 1:  $-40^{\circ}\text{C}$  至  $125^{\circ}\text{C}$
  - 器件 HBM ESD 分类等级 2
  - 器件 CDM ESD 分类等级 C4B
  - 可承受 40V 负载突降
- 提供功能安全
  - 可帮助创建功能安全系统设计的文档
- 单通道智能高侧开关, 具有  $8\text{m}\Omega$   $R_{\text{ON}}$  ( $T_{\text{J}} = 25^{\circ}\text{C}$ )
- 可通过可调电流限制提高系统级可靠性
  - 电流限制设定范围为  $6.4\text{A}$  至  $70\text{A}$
  - 版本 F:  $94\text{A}$  固定  $I_{\text{LIM}}$
- 强大的集成输出保护:
  - 集成热保护
  - 接地短路和电池短路保护
  - 反向电池事件保护包括 FET 通过反向电流自动开启
  - 在失电和接地失效时自动关闭
  - 集成输出钳位对电感负载进行消磁
  - 可配置故障处理
- 可对模拟检测输出进行配置, 以精确测量:
  - 负载电流
  - 器件温度
- 通过 SNS 引脚或  $\overline{\text{FLT}}$  引脚提供故障指示
  - 开路负载和电池短路检测

## 2 应用

- 汽车显示模块
- 65W 汽车前照灯
- ADAS 模块
- 座椅舒适模块
- 变速器控制单元
- HVAC 控制模块
- 车身控制模块
- 白炽灯和 LED 照明

## 3 说明

TPS1HB08-Q1 器件是一款适用于 12V 汽车系统的智能高侧开关。该器件集成了强大的保护和诊断功能, 以确保即使在汽车系统中发生短路等有害事件时也能提供输出端口保护。该器件通过可靠的电流限制来防止故障, 根据器件型号不同, 电流限制在  $6.4\text{A}$  至  $70\text{A}$  范围内可调或可设置为  $94\text{A}$ 。凭借较高的电流限制范围, 该器件可用于需要大瞬态电流的负载, 而低电流限制范围可为不需要峰值电流的负载提供更好的保护。该器件能够可靠地驱动各种负载分布。

TPS1HB08-Q1 还能够提供可改进负载诊断的高精度模拟电流检测。通过向系统 MCU 报告负载电流和器件温度, 该器件可实现预测性维护和负载诊断, 从而延长系统寿命。

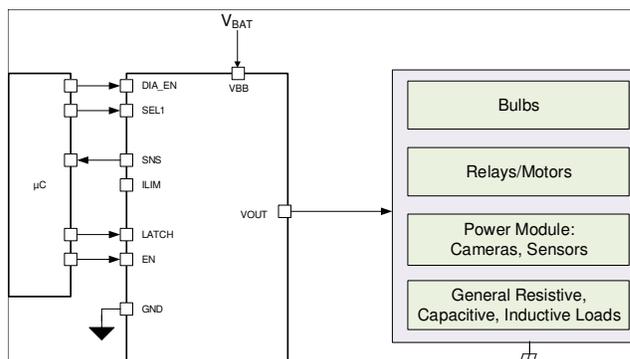
TPS1HB08-Q1 采用 HTSSOP 封装, 可减小 PCB 尺寸。

### 器件信息(1)

器件型号	封装	封装尺寸 (标称值)
TPS1HB08-Q1	HTSSOP (16)	5.0mm x 4.40mm

(1) 如需了解所有可用封装, 请参阅数据表末尾的可订购产品附录。

### 简化原理图



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## 4 修订历史记录

<b>Changes from Revision B (December 2019) to Revision C</b>	<b>Page</b>
• Deleted tablenote from the <a href="#">Device Comparison Table</a> to remove product preview from Versions A and B .....	<b>3</b>

<b>Changes from Revision A (December 2019) to Revision B</b>	<b>Page</b>
• 向 <a href="#">特性</a> 部分添加了提供功能安全的链接 .....	<b>1</b>

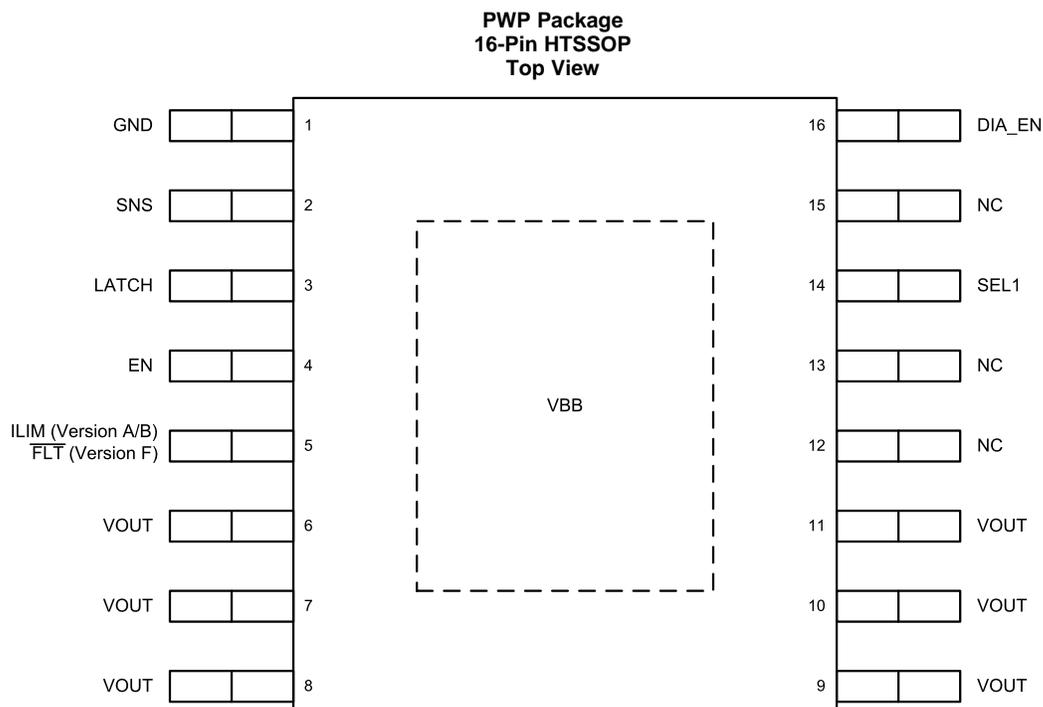
<b>Changes from Original (May 2019) to Revision A</b>	<b>Page</b>
• 将“预告信息”更改为“生产数据” .....	<b>1</b>

## 5 Device Comparison Table

**Table 1. Device Options**

Device Version	Part Number	Current Limit	Current Limit Range	Overcurrent Behavior
A	TPS1HB08A-Q1	Resistor Programmable	6.4 A to 32 A	Disable switch immediately
B	TPS1HB08B-Q1	Resistor Programmable	14 A to 70 A	Disable switch immediately
F	TPS1HB08F-Q1	Internally Set	94 A	Disable switch immediately

## 6 Pin Configuration and Functions


**Pin Functions**

NAME	PIN		I/O	DESCRIPTION
	Version A/B	Version F		
GND	1	1	—	Device ground
SNS	2	2	O	Sense output
LATCH	3	3	I	Sets fault handling behavior (latched or auto-retry)
EN	4	4	I	Control input, active high
ILIM	5	-	O	Connect resistor to set current-limit threshold
FLT	-	5	O	Open drain output with pulldown to signal fault.
VOUT	6 - 11	6 - 11	O	Channel output
NC	12 - 13, 15	12 - 13, 15	I	No Connect, leave floating
SEL1	14	14	I	Diagnostics select. No functionality on device version F; connect to IC GND through R <sub>PROT</sub> resistor
DIA_EN	16	16	I	Diagnostic enable, active high
VBB	Exposed pad	Exposed pad	I	Power supply input

## 6.1 Recommended Connections for Unused Pins

The TPS1HB08-Q1 is designed to provide an enhanced set of diagnostic and protection features. However, if the system design only allows for a limited number of I/O connections, some pins may be considered as optional.

**Table 2. Connections for Optional Pins**

PIN NAME	CONNECTION IF NOT USED	IMPACT IF NOT USED
SNS	Ground through 1-kΩ resistor	Analog sense is not available.
LATCH	Float or ground through R <sub>PROT</sub> resistor	With LATCH unused, the device will auto-retry after a fault. If latched behavior is desired, but the system describes limited I/O, it is possible to use one microcontroller output to control the latch function of several high-side channels.
ILIM (Version A/B)	Float	If the ILIM pin is left floating, the device will be set to the default internal current-limit threshold. This is considered a fault state for the device.
$\overline{\text{FLT}}$ (Version F)	Float	If the $\overline{\text{FLT}}$ pin is unused, the system cannot read faults from the output.
SEL1	Ground through R <sub>PROT</sub> resistor	SEL1 selects the T <sub>J</sub> sensing feature. With SEL1 unused, only current sensing and open load detection are available. If unused, must be grounded through a resistor to engage FET turn-on during reverse battery.
DIA_EN	Float or ground through R <sub>PROT</sub> resistor	With DIA_EN unused, the analog sense, open-load, and short-to-battery diagnostics are not available.

## 7 Specifications

### 7.1 Absolute Maximum Ratings

Over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

		MIN	MAX	UNIT
Maximum continuous supply voltage, $V_{BB}$			36	V
Load dump voltage, $V_{LD}$	ISO16750-2:2010(E)		40	V
Reverse battery voltage, $V_{Rev}$ , $t \leq 3$ minutes		-18		V
Enable pin voltage, $V_{EN}$		-1	7	V
LATCH pin voltage, $V_{LATCH}$		-1	7	V
Diagnostic Enable pin voltage, $V_{DIA\_EN}$		-1	7	V
Sense pin voltage, $V_{SNS}$		-1	18	V
Select pin voltage, $V_{SEL}$		-1	7	V
Reverse ground current, $I_{GND}$		$V_{BB} < 0$ V		-50 mA
Energy dissipation during turnoff, $E_{TOFF}$		Single pulse, $L_{OUT} = 5$ mH, $T_{J,start} = 125^\circ\text{C}$		95 <sup>(2)</sup> mJ
Energy dissipation during turnoff, $E_{TOFF}$		Repetitive pulse, $L_{OUT} = 5$ mH, $T_{J,start} = 125^\circ\text{C}$		56 <sup>(2)</sup> mJ
Maximum junction temperature, $T_J$			150	$^\circ\text{C}$
Storage temperature, $T_{stg}$		-65	150	$^\circ\text{C}$

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute maximum rated conditions for extended periods may affect device reliability.
- (2) For further details, see the section regarding switch-off of an inductive load.

### 7.2 ESD Ratings

				VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per AEC Q100-002 <sup>(1)</sup>	All pins except $V_{BB}$ and $V_{OUT}$	$\pm 2000$	V
			$V_{BB}$ and $V_{OUT}$	$\pm 4000$	
		Charged-device model (CDM), per AEC Q100-011	All pins	$\pm 750$	

- (1) AEC-Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specifications.

### 7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

		MIN	MAX	UNIT
$V_{BB}$	Nominal supply voltage <sup>(1)</sup>	6	18	V
$V_{BB}$	Extended supply voltage <sup>(2)</sup>	3	28	V
$V_{EN}$	Enable voltage	-1	5.5	V
$V_{LATCH}$	LATCH voltage	-1	5.5	V
$V_{DIA\_EN}$	Diagnostic Enable voltage	-1	5.5	V
$V_{SEL1}$	Select voltage	-1	5.5	V
$V_{SNS}$	Sense voltage	-1	7	V

- (1) All operating voltage conditions are measured with respect to device GND
- (2) Device will function within extended operating range, however some parametric values might not apply

### 7.4 Thermal Information

THERMAL METRIC <sup>(1) (2)</sup>		TPS1HB08-Q1	UNIT
		PWP (HTSSOP)	
		16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	32.6	$^\circ\text{C}/\text{W}$

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.
- (2) The thermal parameters are based on a 4-layer PCB according to the JESD51-5 and JESD51-7 standards.

**Thermal Information (continued)**

THERMAL METRIC <sup>(1)</sup> <sup>(2)</sup>		TPS1HB08-Q1	UNIT
		PWP (HTSSOP)	
		16 PINS	
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	25.3	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	9.2	°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	2.3	°C/W
$\Psi_{JB}$	Junction-to-board characterization parameter	9.3	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	1.0	°C/W

**7.5 Electrical Characteristics**
 $V_{BB} = 6\text{ V to }18\text{ V}$ ,  $T_J = -40^\circ\text{C to }150^\circ\text{C}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>INPUT VOLTAGE AND CURRENT</b>						
$V_{DSCLAMP}$	$V_{DS}$ clamp voltage		40		46	V
$V_{BBCLAMP}$	$V_{BB}$ clamp voltage		58		76	V
$V_{UVLOF}$	$V_{BB}$ undervoltage lockout falling	Measured with respect to the GND pin of the device	2.0		3	V
$V_{UVLOR}$	$V_{BB}$ undervoltage lockout rising	Measured with respect to the GND pin of the device	2.2		3	V
$I_{SB}$	Standby current (total device leakage including MOSFET)	$V_{BB} = 13.5\text{ V}$ , $T_J = 25^\circ\text{C}$ $V_{EN} = V_{DIA\_EN} = 0\text{ V}$ , $V_{OUT} = 0\text{ V}$			0.1	$\mu\text{A}$
		$V_{BB} = 13.5\text{ V}$ , $T_J = 85^\circ\text{C}$ , $V_{EN} = V_{DIA\_EN} = 0\text{ V}$ , $V_{OUT} = 0\text{ V}$			0.5	$\mu\text{A}$
$I_{L\_NOM}$	Continuous load current	$T_{AMB} = 70^\circ\text{C}$		11		A
$I_{OUT(standby)}$	Output leakage current	$V_{BB} = 13.5\text{ V}$ , $T_J = 25^\circ\text{C}$ $V_{EN} = V_{DIA\_EN} = 0\text{ V}$ , $V_{OUT} = 0\text{ V}$		0.01	0.5	$\mu\text{A}$
		$V_{BB} = 13.5\text{ V}$ , $T_J = 125^\circ\text{C}$ $V_{EN} = V_{DIA\_EN} = 0\text{ V}$ , $V_{OUT} = 0\text{ V}$			3	$\mu\text{A}$
$I_{DIA}$	Current consumption in diagnostic mode	$V_{BB} = 13.5\text{ V}$ , $I_{SNS} = 0\text{ mA}$ $V_{EN} = 0\text{ V}$ , $V_{DIA\_EN} = 5\text{ V}$ , $V_{OUT} = 0\text{ V}$		3	6	mA
$I_Q$	Quiescent current	$V_{BB} = 13.5\text{ V}$ $V_{EN} = V_{DIA\_EN} = 5\text{ V}$ , $I_{OUT} = 0\text{ A}$		3	6	mA
$t_{STBY}$	Standby mode delay time	$V_{EN} = V_{DIA\_EN} = 0\text{ V}$ to standby	12	17	22	ms
<b>RON CHARACTERISTICS</b>						
$R_{ON}$	On-resistance (Includes MOSFET and package)	$T_J = 25^\circ\text{C}$ , $6\text{ V} \leq V_{BB} \leq 28\text{ V}$		8		$\text{m}\Omega$
		$T_J = 150^\circ\text{C}$ , $6\text{ V} \leq V_{BB} \leq 28\text{ V}$			16	$\text{m}\Omega$
		$T_J = 25^\circ\text{C}$ , $3\text{ V} \leq V_{BB} \leq 6\text{ V}$			12	$\text{m}\Omega$
$R_{ON(REV)}$	On-resistance during reverse polarity	$T_J = 25^\circ\text{C}$ , $-18\text{ V} \leq V_{BB} \leq -8\text{ V}$		8		$\text{m}\Omega$
		$T_J = 105^\circ\text{C}$ , $-18\text{ V} \leq V_{BB} \leq -8\text{ V}$			16	$\text{m}\Omega$
<b>CURRENT SENSE CHARACTERISTICS</b>						
$K_{SNS}$	Current sense ratio $I_{OUT} / I_{SNS}$	$I_{OUT} = 1\text{ A}$		5000		

**Electrical Characteristics (continued)**
 $V_{BB} = 6\text{ V to }18\text{ V}$ ,  $T_J = -40^\circ\text{C to }150^\circ\text{C}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_{SNSI}$	Current sense current and accuracy	$V_{EN} = V_{DIA\_EN} = 5\text{ V}$ , $V_{SEL1} = 0\text{ V}$	$I_{OUT} = 10\text{ A}$		2.000		mA
					-5		5.3
			$I_{OUT} = 3\text{ A}$		0.6		mA
					-5		5.3
			$I_{OUT} = 1\text{ A}$		0.2		mA
					-5		5.3
			$I_{OUT} = 300\text{ mA}$		0.06043		mA
					-4.6		6.2
$I_{OUT} = 100\text{ mA}$		0.0206		mA			
		-13.6		15.1	%		
$I_{OUT} = 50\text{ mA}$		0.0106		mA			
		-28.3		30.3	%		
$I_{OUT} = 20\text{ mA}$		0.0046		mA			
		-56		57.3	%		
<b>TJ SENSE CHARACTERISTICS</b>							
$I_{SNSST}$	Temperature sense current Device Version A/B	$V_{DIA\_EN} = 5\text{ V}$ , $V_{SEL1} = 5\text{ V}$	$T_J = -40^\circ\text{C}$	0.01	0.12	0.38	mA
			$T_J = 25^\circ\text{C}$	0.72	0.85	0.98	mA
			$T_J = 85^\circ\text{C}$	1.25	1.52	1.79	mA
			$T_J = 125^\circ\text{C}$	1.61	1.96	2.31	mA
			$T_J = 150^\circ\text{C}$	1.80	2.25	2.70	mA
$dI_{SNSST}/dT$	Coefficient			0.0112			mA/°C
<b>SNS CHARACTERISTICS</b>							
$I_{SNSFH}$	$I_{SNS}$ fault high-level	$V_{DIA\_EN} = 5\text{ V}$ , $V_{SEL1} = 0\text{ V}$		4	4.5	5.3	mA
$I_{SNSleak}$	$I_{SNS}$ leakage	$V_{DIA\_EN} = 0\text{ V}$				1	µA
<b>CURRENT LIMIT CHARACTERISTICS</b>							
$I_{CL}$	Current limit threshold	Device Version A, $T_J = -40^\circ\text{C to }150^\circ\text{C}$	$R_{ILIM} = \text{GND, open, or out of range}$		42		A
			$R_{ILIM} = 5\text{ k}\Omega$	27.2	32	36.8	A
			$R_{ILIM} = 25\text{ k}\Omega$	4.7	6.4	8.1	A
		Device Version B, $T_J = -40^\circ\text{C to }150^\circ\text{C}$	$R_{ILIM} = \text{GND, open, or out of range}$		104		A
			$R_{ILIM} = 5\text{ k}\Omega$	47.1	70	84.2	A
			$R_{ILIM} = 25\text{ k}\Omega$	9.9	14	17.8	A
Device Version F	$T_J = -40^\circ\text{C to }60^\circ\text{C}$	80	94	105	A		
	$T_J = 150^\circ\text{C}$	68	77	86.1	A		
$K_{CL}$	Current Limit Ratio	Version A		120	160	208	A * kΩ
		Version B		245	350	437.5	A * kΩ
<b>FAULT CHARACTERISTICS</b>							
$V_{OL}$	Open-load (OL) detection voltage	$V_{EN} = 0\text{ V}$ , $V_{DIA\_EN} = 5\text{ V}$ , $V_{SEL1} = 0\text{ V}$		2	3	4	V
$V_{FLT}$	FLT low output voltage (Version F only)	$I_{FLT} = 1\text{ mA}$				1	V
$t_{OL1}$	OL and STB indication-time from EN falling	$V_{EN} = 5\text{ V to }0\text{ V}$ , $V_{DIA\_EN} = 5\text{ V}$ , $V_{SEL1} = 0\text{ V}$ $I_{OUT} = 0\text{ mA}$ , $V_{OUT} = 4\text{ V}$		300	500	700	µs
$t_{OL2}$	OL and STB indication-time from DIA_EN rising	$V_{EN} = 0\text{ V}$ , $V_{DIA\_EN} = 0\text{ V to }5\text{ V}$ , $V_{SEL1} = 0\text{ V}$ $I_{OUT} = 0\text{ mA}$ , $V_{OUT} = 4\text{ V}$		2	20	50	µs
$t_{OL3}$	OL and STB indication-time from VOUT rising	$V_{EN} = 0\text{ V}$ , $V_{DIA\_EN} = 5\text{ V}$ , $V_{SEL1} = 0\text{ V}$ $I_{OUT} = 0\text{ mA}$ , $V_{OUT} = 0\text{ V to }4\text{ V}$		2	20	50	µs

## Electrical Characteristics (continued)

 $V_{BB} = 6\text{ V to }18\text{ V}$ ,  $T_J = -40^\circ\text{C to }150^\circ\text{C}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$T_{ABS}$	Thermal shutdown		150			$^\circ\text{C}$
$T_{HYS}$	Thermal shutdown hysteresis		20	25	30	$^\circ\text{C}$
$t_{FAULT}$	Fault shutdown indication-time	$V_{DIA\_EN} = 5\text{ V}$ Time between switch shutdown and $I_{SNS}$ settling at $I_{SNSFH}$			50	$\mu\text{s}$
$t_{RETRY}$	Retry time	Time from fault shutdown until switch re-enable (thermal shutdown or current limit).	1	2	3	ms
<b>EN PIN CHARACTERISTICS</b>						
$V_{IL\_EN}$	Input voltage low-level	No GND network diode			0.8	V
$V_{IH\_EN}$	Input voltage high-level	No GND network diode	2.0			V
$V_{IHYS\_EN}$	Input voltage hysteresis			350		mV
$R_{EN}$	Internal pulldown resistor		0.5	1	2	$\text{M}\Omega$
$I_{IL\_EN}$	Input current low-level	$V_{EN} = 0.8\text{ V}$		0.8		$\mu\text{A}$
$I_{IH\_EN}$	Input current high-level	$V_{EN} = 5\text{ V}$		5.0		$\mu\text{A}$
<b>DIA_EN PIN CHARACTERISTICS</b>						
$V_{IL\_DIA\_EN}$	Input voltage low-level	No GND network diode			0.8	V
$V_{IH\_DIA\_EN}$	Input voltage high-level	No GND network diode	2.0			V
$V_{IHYS\_DIA\_EN}$	Input voltage hysteresis			350		mV
$R_{DIA\_EN}$	Internal pulldown resistor		0.5	1	2	$\text{M}\Omega$
$I_{IL\_DIA\_EN}$	Input current low-level	$V_{DIA\_EN} = 0.8\text{ V}$		0.8		$\mu\text{A}$
$I_{IH\_DIA\_EN}$	Input current high-level	$V_{DIA\_EN} = 5\text{ V}$		5.0		$\mu\text{A}$
<b>SEL1 PIN CHARACTERISTICS</b>						
$V_{IL\_SEL1}$	Input voltage low-level	No GND network diode			0.8	V
$V_{IH\_SEL1}$	Input voltage high-level	No GND network diode	2.0			V
$V_{IHYS\_SEL1}$	Input voltage hysteresis			350		mV
$R_{SEL1}$	Internal pulldown resistor		0.5	1	2	$\text{M}\Omega$
$I_{IL\_SEL1}$	Input current low-level	$V_{SEL1} = 0.8\text{ V}$		0.8		$\mu\text{A}$
$I_{IH\_SEL1}$	Input current high-level	$V_{SEL1} = 5\text{ V}$		5		$\mu\text{A}$
<b>LATCH PIN CHARACTERISTICS</b>						
$V_{IL\_LATCH}$	Input voltage low-level	No GND network diode			0.8	V
$V_{IH\_LATCH}$	Input voltage high-level	No GND network diode	2.0			V
$V_{IHYS\_LATCH}$	Input voltage hysteresis			350		mV
$R_{LATCH}$	Internal pulldown resistor		0.5	1	2	$\text{M}\Omega$
$I_{IL\_LATCH}$	Input current low-level	$V_{LATCH} = 0.8\text{ V}$		0.8		$\mu\text{A}$
$I_{IH\_LATCH}$	Input current high-level	$V_{LATCH} = 5\text{ V}$		5.0		$\mu\text{A}$

## 7.6 SNS Timing Characteristics

 $V_{BB} = 6\text{ V to }18\text{ V}$ ,  $T_J = -40^\circ\text{C to }+150^\circ\text{C}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>SNS TIMING - CURRENT SENSE</b>						
$t_{SNSION1}$	Settling time from rising edge of DIA_EN	$V_{EN} = 5\text{ V}$ , $V_{DIA\_EN} = 0\text{ V to }5\text{ V}$ $R_{SNS} = 1\text{ k}\Omega$ , $R_L = 2.6\ \Omega$			40	$\mu\text{s}$
$t_{SNSION2}$	Settling time from rising edge of EN and DIA_EN	$V_{EN} = V_{DIA\_EN} = 0\text{ V to }5\text{ V}$ $R_{SNS} = 1\text{ k}\Omega$ , $R_L = 2.6\ \Omega$			200	$\mu\text{s}$

## SNS Timing Characteristics (continued)

 $V_{BB} = 6\text{ V to }18\text{ V}$ ,  $T_J = -40^\circ\text{C to }+150^\circ\text{C}$  (unless otherwise noted)

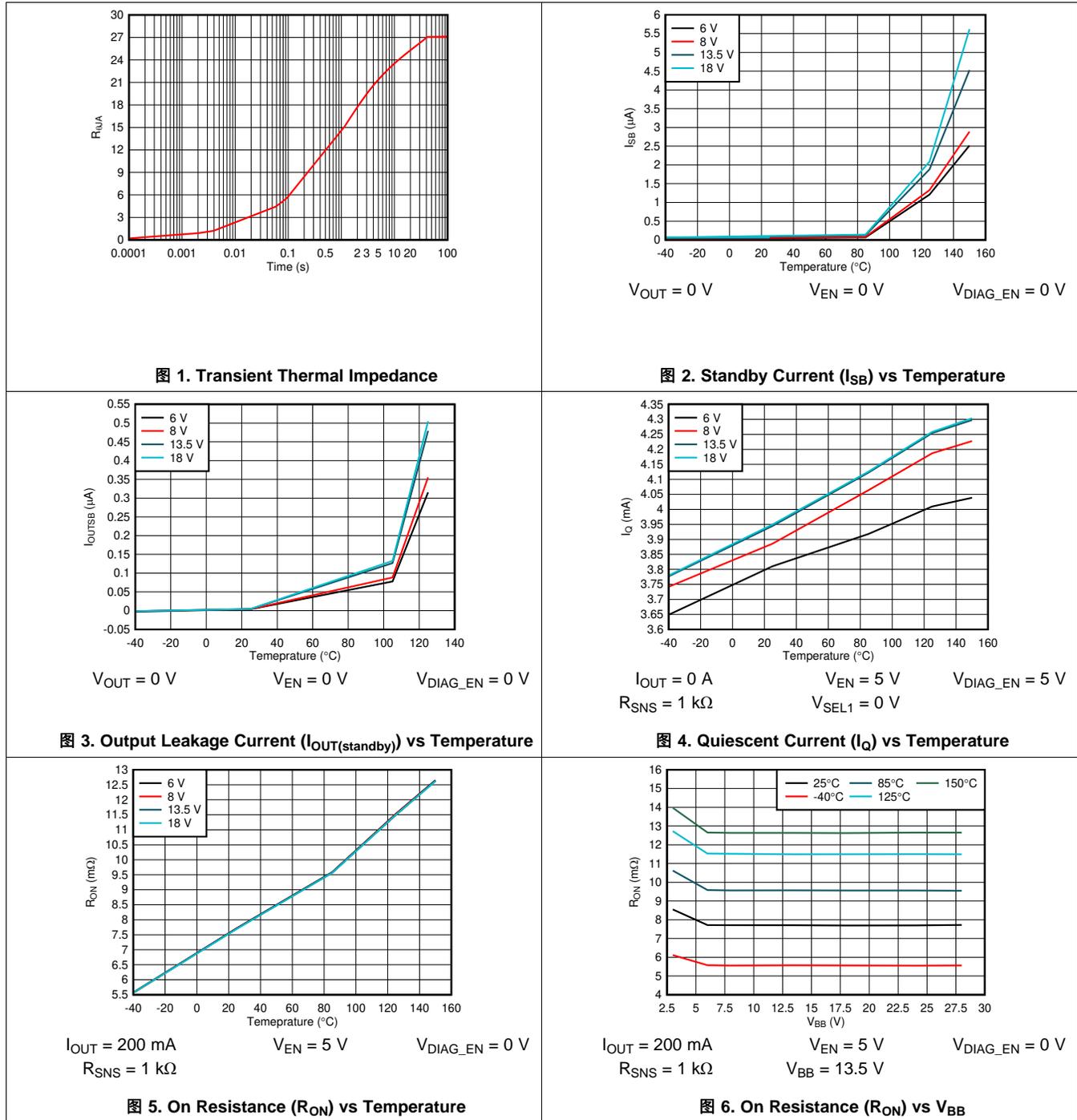
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{\text{SNSION3}}$	Settling time from rising edge of EN	$V_{\text{EN}} = 0\text{ V to }5\text{ V}$ , $V_{\text{DIA\_EN}} = 5\text{ V}$ $R_{\text{SNS}} = 1\text{ k}\Omega$ , $R_L = 2.6\ \Omega$			165	$\mu\text{s}$
$t_{\text{SNSIOFF1}}$	Settling time from falling edge of DIA_EN	$V_{\text{EN}} = 5\text{ V}$ , $V_{\text{DIA\_EN}} = 5\text{ V to }0\text{ V}$ $R_{\text{SNS}} = 1\text{ k}\Omega$ , $R_L = 2.6\ \Omega$			20	$\mu\text{s}$
$t_{\text{SETTLEH}}$	Settling time from rising edge of load step	$V_{\text{EN}} = 5\text{ V}$ , $V_{\text{DIA\_EN}} = 5\text{ V}$ $R_{\text{SNS}} = 1\text{ k}\Omega$ , $I_{\text{OUT}} = 1\text{ A to }5\text{ A}$			20	$\mu\text{s}$
$t_{\text{SETTLEL}}$	Settling time from falling edge of load step	$V_{\text{EN}} = 5\text{ V}$ , $V_{\text{DIA\_EN}} = 5\text{ V}$ $R_{\text{SNS}} = 1\text{ k}\Omega$ , $I_{\text{OUT}} = 5\text{ A to }1\text{ A}$			20	$\mu\text{s}$
<b>SNS TIMING - TEMPERATURE SENSE</b>						
$t_{\text{SNSTON1}}$	Settling time from rising edge of DIA_EN	$V_{\text{EN}} = 5\text{ V}$ , $V_{\text{DIA\_EN}} = 0\text{ V to }5\text{ V}$ $R_{\text{SNS}} = 1\text{ k}\Omega$			40	$\mu\text{s}$
$t_{\text{SNSTON2}}$	Settling time from rising edge of DIA_EN	$V_{\text{EN}} = 0\text{ V}$ , $V_{\text{DIA\_EN}} = 0\text{ V to }5\text{ V}$ $R_{\text{SNS}} = 1\text{ k}\Omega$			70	$\mu\text{s}$
$t_{\text{SNSTOFF}}$	Settling time from falling edge of DIA_EN	$V_{\text{EN}} = X$ , $V_{\text{DIA\_EN}} = 5\text{ V to }0\text{ V}$ $R_{\text{SNS}} = 1\text{ k}\Omega$			20	$\mu\text{s}$
<b>SNS TIMING - MULTIPLEXER</b>						
$t_{\text{MUX}}$	Settling time from temperature sense to current sense	$V_{\text{EN}} = 5\text{ V}$ , $V_{\text{DIA\_EN}} = 5\text{ V}$ $V_{\text{SEL1}} = 5\text{ V to }0\text{ V}$ $R_{\text{SNS}} = 1\text{ k}\Omega$ , $R_L = 2.6\ \Omega$			60	$\mu\text{s}$
	Settling time from current sense to temperature sense	$V_{\text{EN}} = 5\text{ V}$ , $V_{\text{DIA\_EN}} = 5\text{ V}$ $V_{\text{SEL1}} = 0\text{ V to }5\text{ V}$ $R_{\text{SNS}} = 1\text{ k}\Omega$ , $R_L = 2.6\ \Omega$			60	$\mu\text{s}$

## 7.7 Switching Characteristics

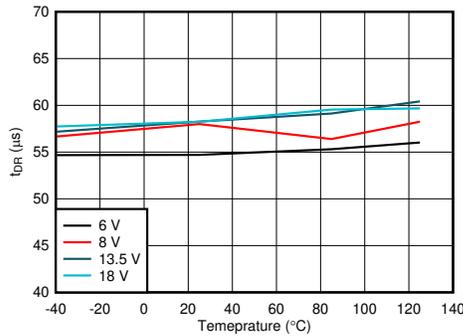
 $V_{BB} = 13.5\text{ V}$ ,  $T_J = -40^\circ\text{C to }+150^\circ\text{C}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{\text{DR}}$	Turnon delay time (from Active)	$V_{\text{BB}} = 13.5\text{ V}$ , $R_L = 2.6\ \Omega$ , 50% EN rising to 10% $V_{\text{OUT}}$ rising	20	60	100	$\mu\text{s}$
$t_{\text{DF}}$	Turnoff delay time	$V_{\text{BB}} = 13.5\text{ V}$ , $R_L = 2.6\ \Omega$ , 50% EN falling to 90% $V_{\text{OUT}}$ Falling	20	60	100	$\mu\text{s}$
$\text{SR}_R$	$V_{\text{OUT}}$ rising slew rate	$V_{\text{BB}} = 13.5\text{ V}$ , 20% to 80% of $V_{\text{OUT}}$ , $R_L = 2.6\ \Omega$	0.1	0.4	0.7	$\text{V}/\mu\text{s}$
$\text{SR}_F$	$V_{\text{OUT}}$ falling slew rate	$V_{\text{BB}} = 13.5\text{ V}$ , 80% to 20% of $V_{\text{OUT}}$ , $R_L = 2.6\ \Omega$	0.1	0.4	0.7	$\text{V}/\mu\text{s}$
$t_{\text{ON}}$	Turnon time (active)	$V_{\text{BB}} = 13.5\text{ V}$ , $R_L = 2.6\ \Omega$ , 50% EN rising to 80% $V_{\text{OUT}}$ rising	39	94	235	$\mu\text{s}$
$t_{\text{OFF}}$	Turnoff time	$V_{\text{BB}} = 13.5\text{ V}$ , $R_L = 2.6\ \Omega$ , 50% EN falling to 20% $V_{\text{OUT}}$ falling	39	94	235	$\mu\text{s}$
$\Delta_{\text{PWM}}$	PWM accuracy - average load current	200- $\mu\text{s}$ enable pulse, $V_S = 13.5\text{ V}$ , $R_L = 2.6\ \Omega$	-25	0	25	%
$t_{\text{ON}} - t_{\text{OFF}}$	Turnon and turnoff matching	200- $\mu\text{s}$ enable pulse	-85	0	85	$\mu\text{s}$
$E_{\text{ON}}$	Switching energy losses during turnon	$V_{\text{BB}} = 13.5\text{ V}$ , $R_L = 2.6\ \Omega$		0.8		mJ
$E_{\text{OFF}}$	Switching energy losses during turnoff	$V_{\text{BB}} = 13.5\text{ V}$ , $R_L = 2.6\ \Omega$		0.8		mJ

### 7.8 Typical Characteristics

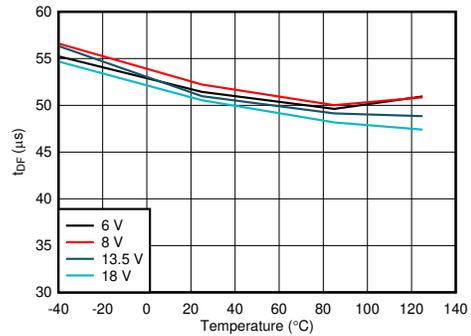


Typical Characteristics (接下页)



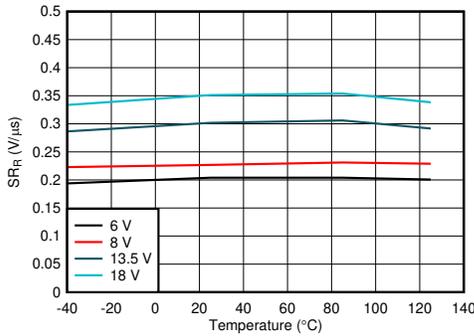
$R_{OUT} = 2.6 \Omega$      $V_{EN} = 0 V \text{ to } 5 V$      $V_{DIAG\_EN} = 0 V$   
 $R_{SNS} = 1 k\Omega$      $V_{BB} = 13.5 V$

图 7. Turn-on Delay Time ( $t_{DR}$ ) vs Temperature



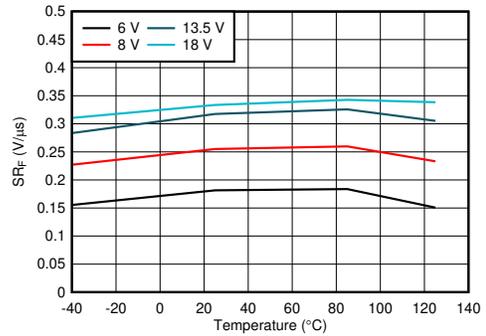
$R_{OUT} = 2.6 \Omega$      $V_{EN} = 5 V \text{ to } 0 V$      $V_{DIAG\_EN} = 0 V$   
 $R_{SNS} = 1 k\Omega$      $V_{BB} = 13.5 V$

图 8. Turn-off Delay Time ( $t_{DF}$ ) vs Temperature



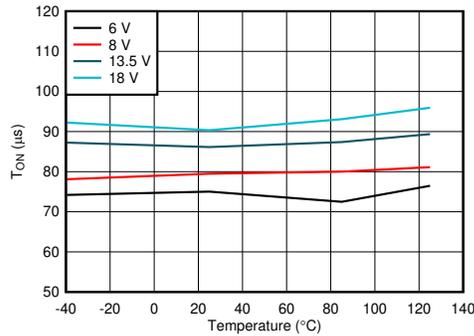
$R_{OUT} = 2.6 \Omega$      $V_{EN} = 0 V \text{ to } 5 V$      $V_{DIAG\_EN} = 0 V$   
 $R_{SNS} = 1 k\Omega$      $V_{BB} = 13.5 V$

图 9.  $V_{OUT}$  Slew Rate Rising ( $SR_R$ ) vs Temperature



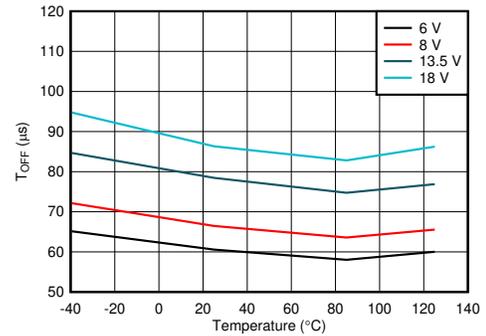
$R_{OUT} = 2.6 \Omega$      $V_{EN} = 5 V \text{ to } 0 V$      $V_{DIAG\_EN} = 0 V$   
 $R_{SNS} = 1 k\Omega$      $V_{BB} = 13.5 V$

图 10.  $V_{OUT}$  Slew Rate Falling ( $SR_F$ ) vs Temperature



$R_{OUT} = 2.6 \Omega$      $V_{EN} = 0 V \text{ to } 5 V$      $V_{DIAG\_EN} = 0 V$   
 $R_{SNS} = 1 k\Omega$      $V_{BB} = 13.5 V$

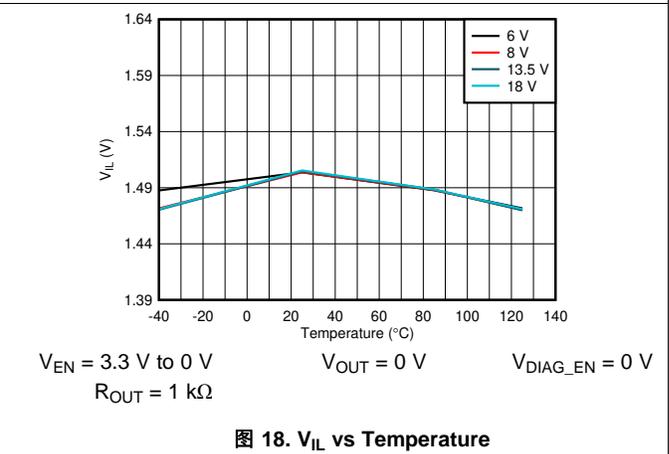
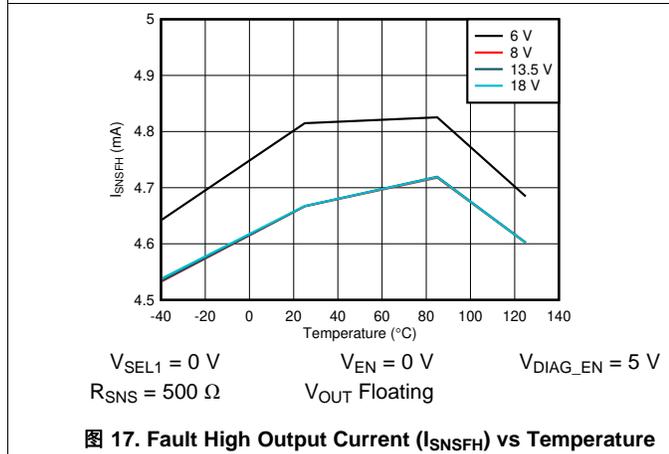
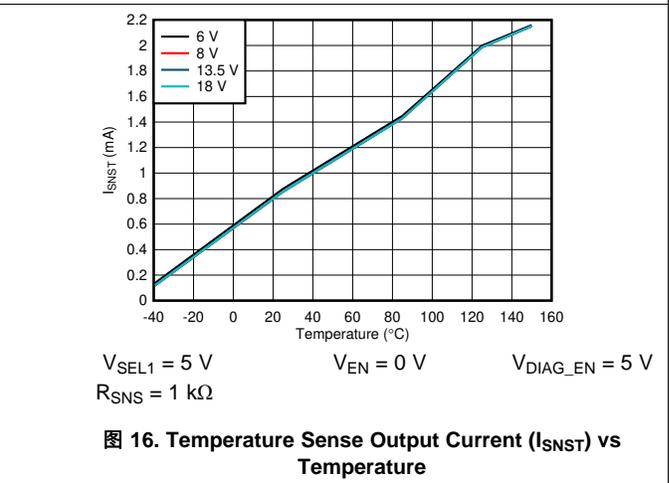
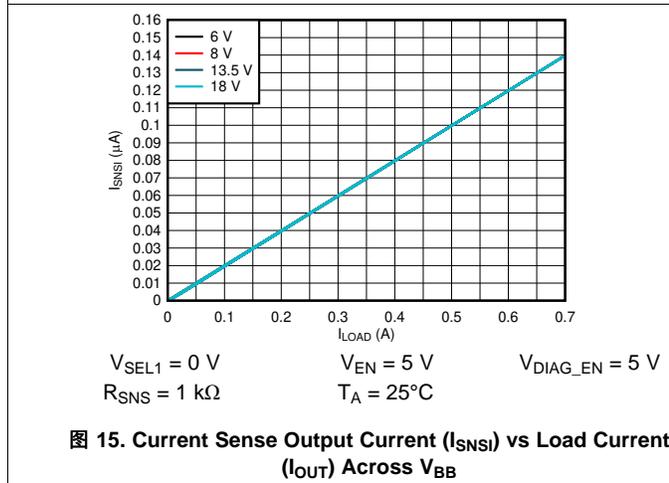
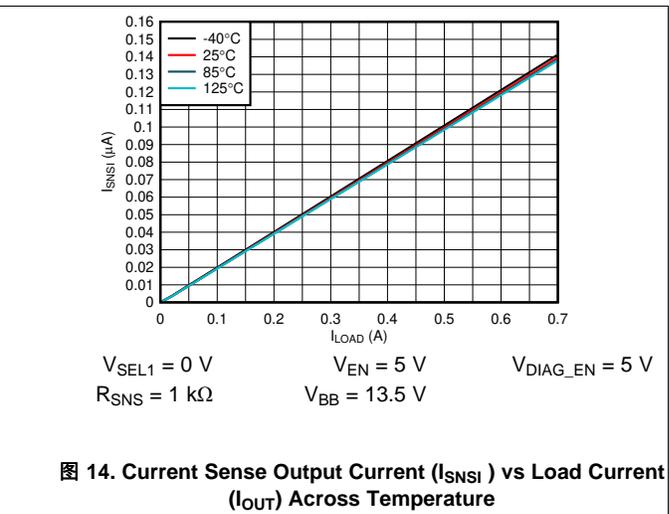
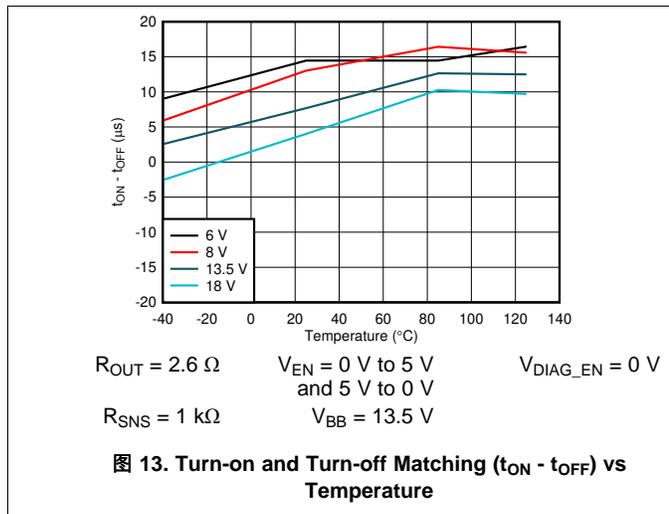
图 11. Turn-on Time ( $t_{ON}$ ) vs Temperature



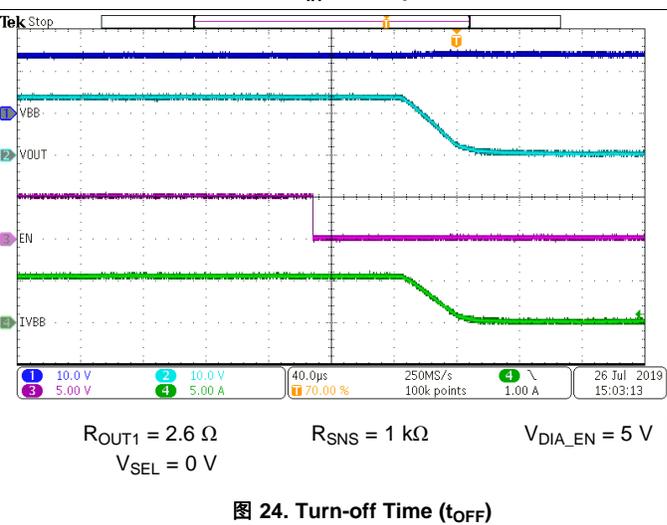
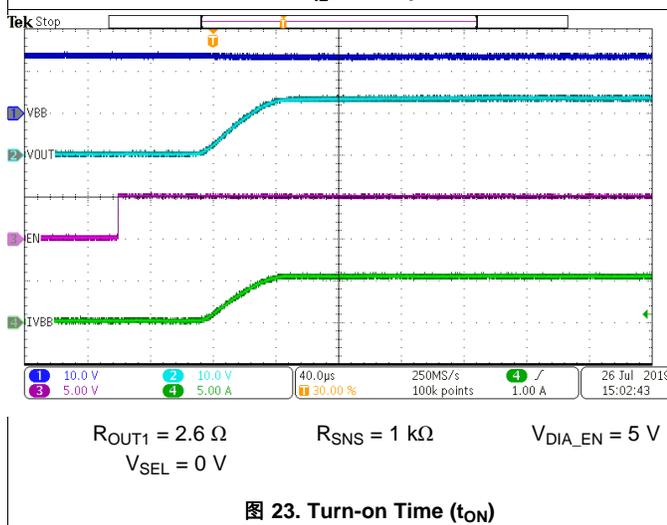
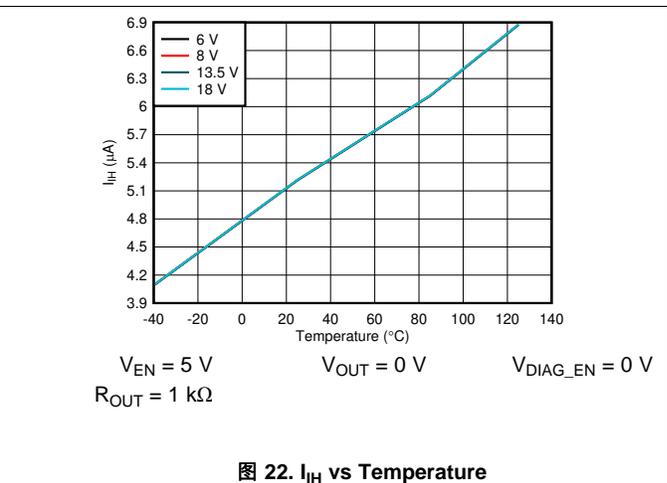
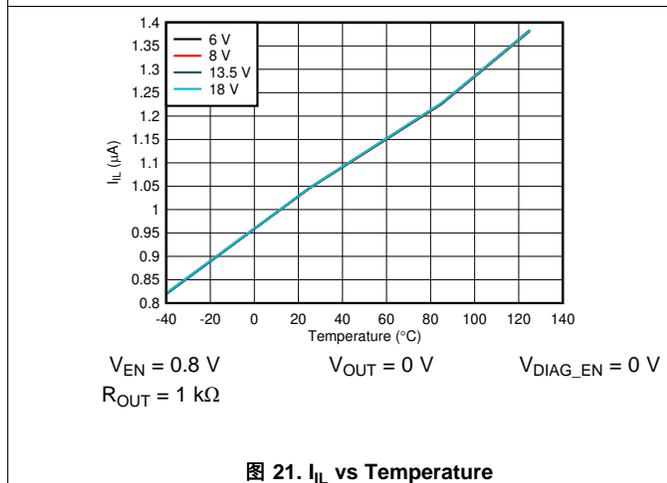
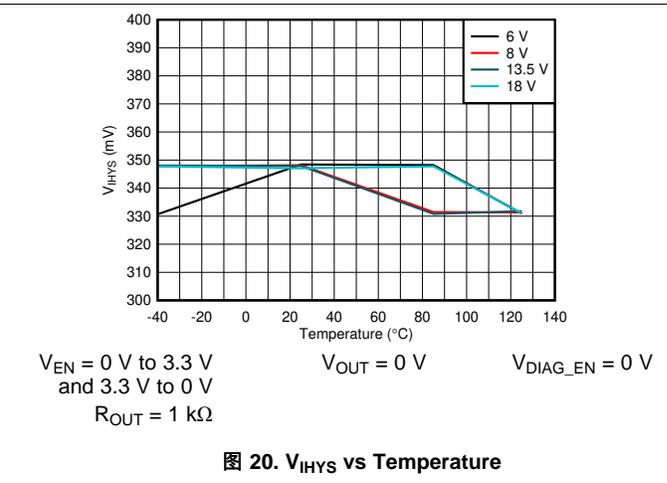
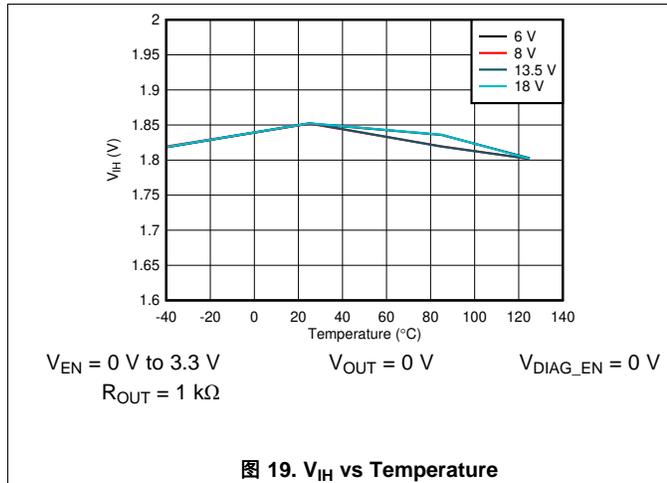
$R_{OUT} = 2.6 \Omega$      $V_{EN} = 5 V \text{ to } 0 V$      $V_{DIAG\_EN} = 0 V$   
 $R_{SNS} = 1 k\Omega$      $V_{BB} = 13.5 V$

图 12. Turn-off Time ( $t_{OFF}$ ) vs Temperature

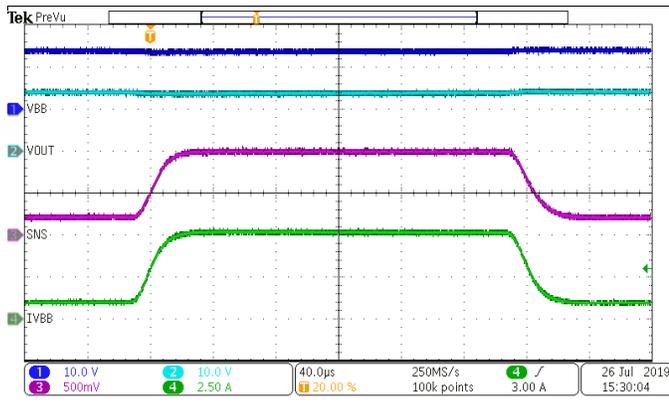
Typical Characteristics (接下页)



Typical Characteristics (接下页)

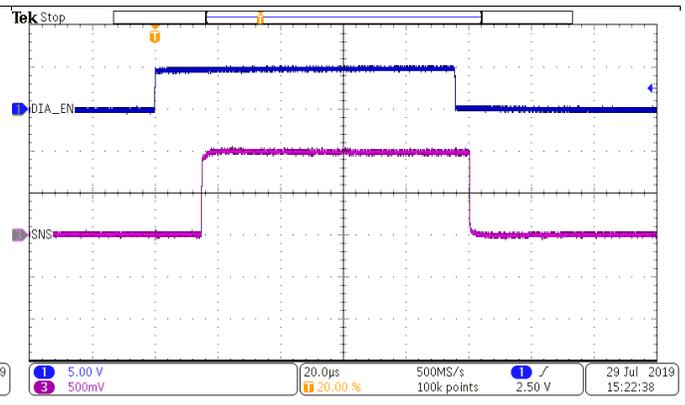


Typical Characteristics (接下页)



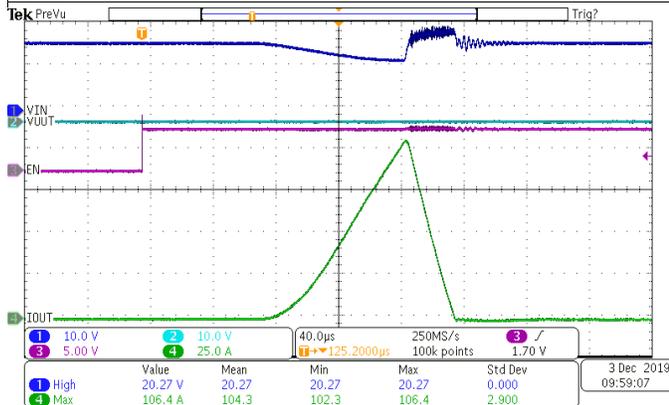
$R_{OUT1} = 2.6 \Omega$        $R_{SNS} = 1 \text{ k}\Omega$        $V_{SEL} = 0 \text{ V}$   
 $I_{OUT1} = 1 \text{ A to } 5 \text{ A}$        $V_{BB} = 13.5 \text{ V}$

图 25.  $I_{SNS}$  Settling time ( $t_{SNSION1}$ ) on Load Step



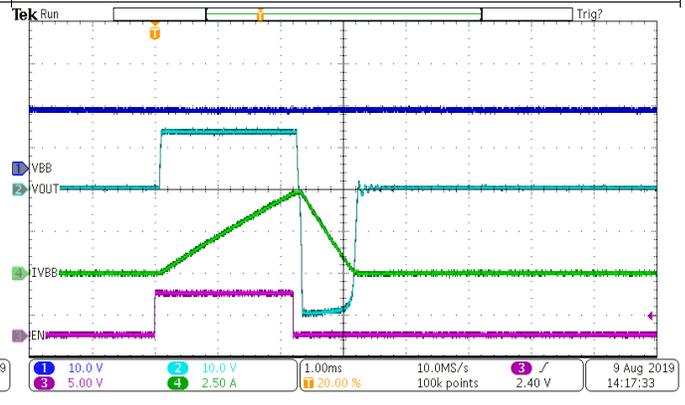
$V_{BB} = 13.5 \text{ V}$        $T_A = 25^\circ\text{C}$        $I_{OUT1} = 5 \text{ A}$   
 $V_{EN} = 0 \text{ V to } 5 \text{ V}$

图 26. SNS Output Current Measurement Enable on DIAG\_EN PWM



$L_{OUT} = 5 \mu\text{H to GND}$        $R_{SNS} = 1 \text{ k}\Omega$        $V_{SEL} = 0 \text{ V}$   
 $V_{EN} = 0 \text{ V to } 5 \text{ V}$        $V_{DIAG\_EN} = 5 \text{ V}$        $T_A = 25^\circ\text{C}$

图 27. Device Version F Short Circuit Event



$V_{BB} = 13.5 \text{ V}$        $T_A = 25^\circ\text{C}$        $L_{OUT} = 5 \text{ mH}$

图 28. 5 mH Inductive Load Demagnetization

## 8 Parameter Measurement Information

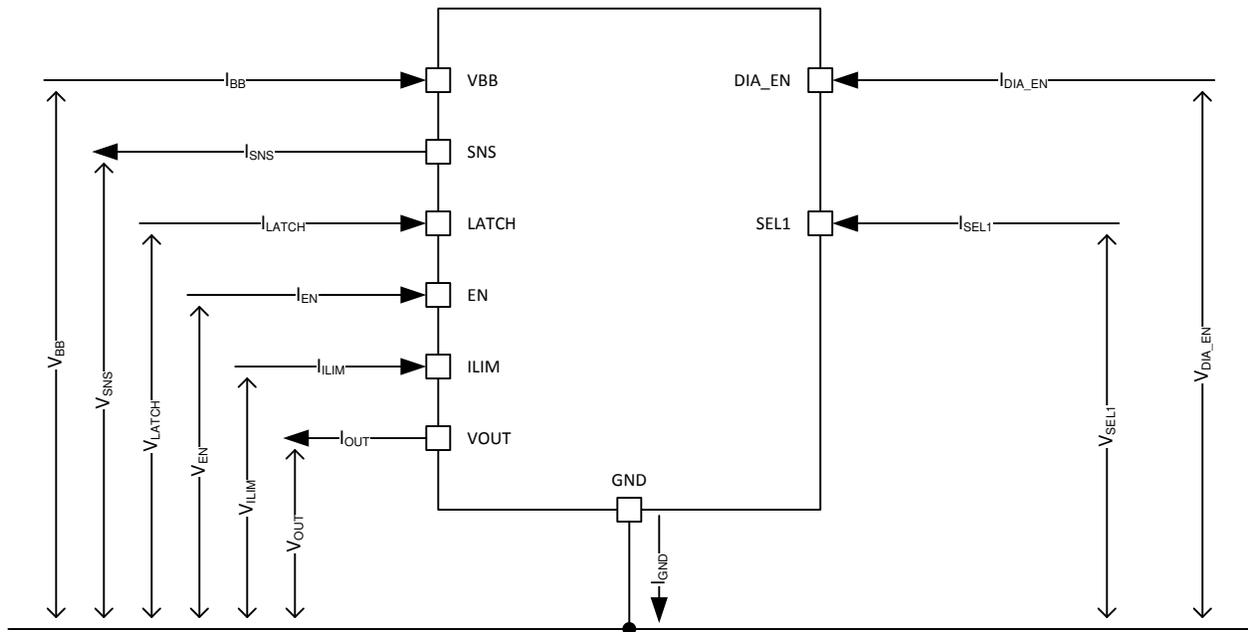
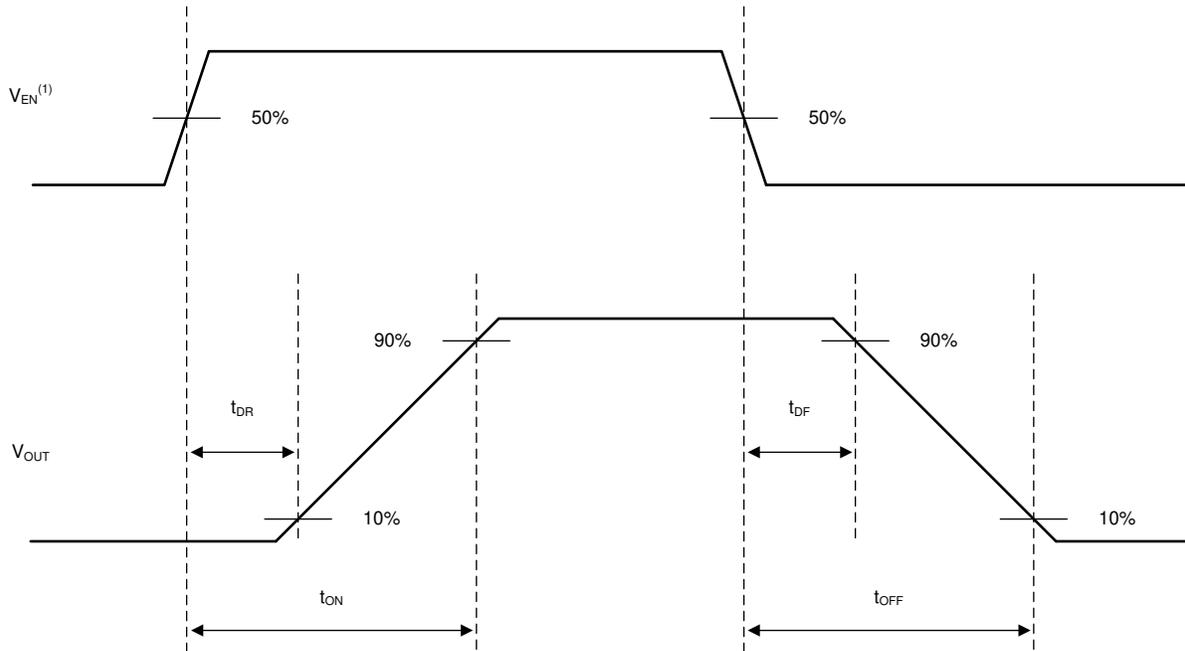
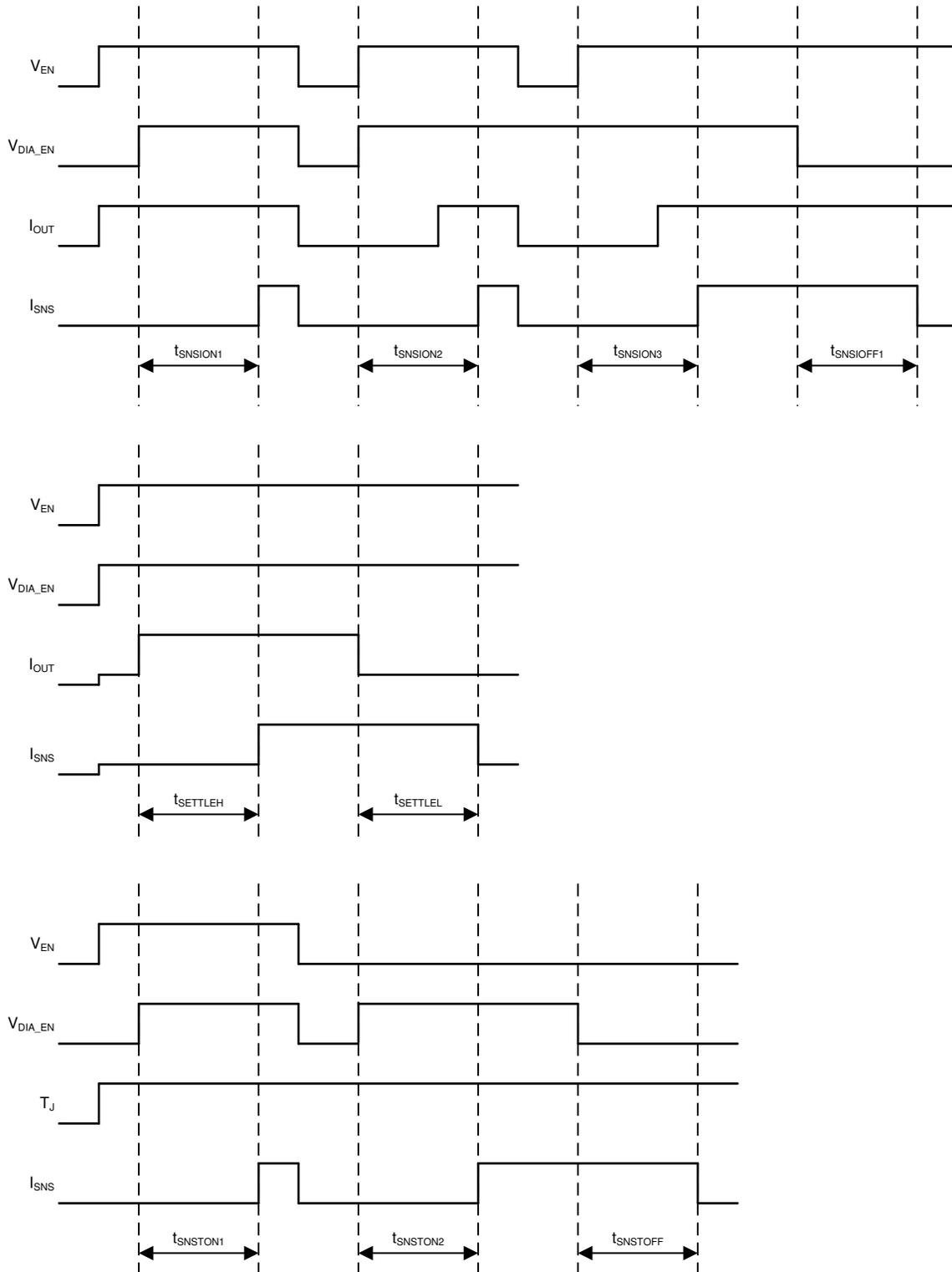


图 29. Parameter Definitions



Rise and fall time of  $V_{EN}$  is 100 ns.

图 30. Switching Characteristics Definitions

**Parameter Measurement Information (接下页)**


NOTES: Rise and fall times of control signals are 100 ns. Control signals include: EN, DIA\_EN, SEL1  
SEL1 pin must be set to the appropriate value.

**图 31. SNS Timing Characteristics Definitions**

## 9 Detailed Description

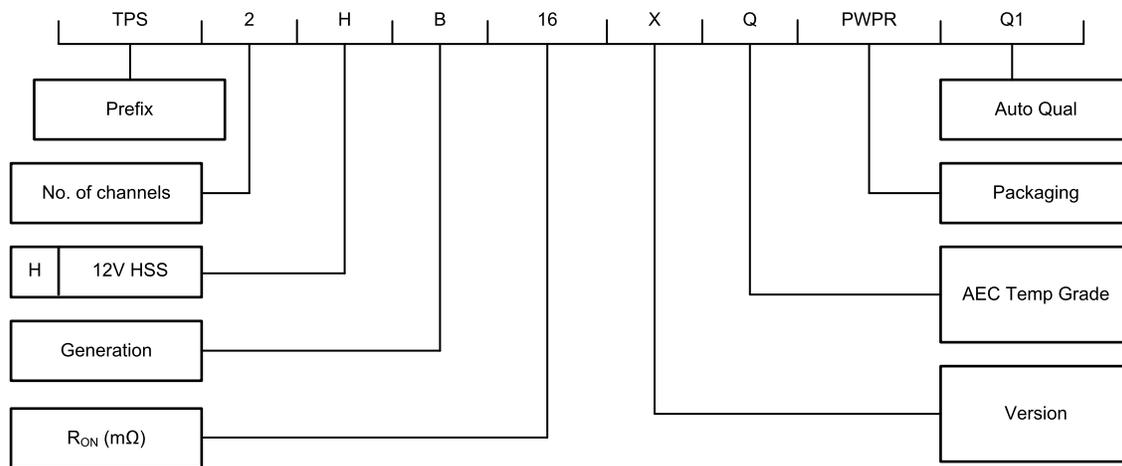
### 9.1 Overview

The TPS1HB08-Q1 device is a single-channel smart high-side switch intended for use with 12-V automotive batteries. Many protection and diagnostic features are integrated in the device.

Diagnostics features include the analog SNS output that is capable of providing a signal that is proportional to load current or device temperature. The high-accuracy load current sense allows for diagnostics of complex loads. Version F of the device includes an open drain FLT pin that indicates device fault states.

This device includes protection through thermal shutdown, current limiting, transient withstand, and reverse battery operation. For more details on the protection features, refer to the [Feature Description](#) and [Application Information](#) sections of the document.

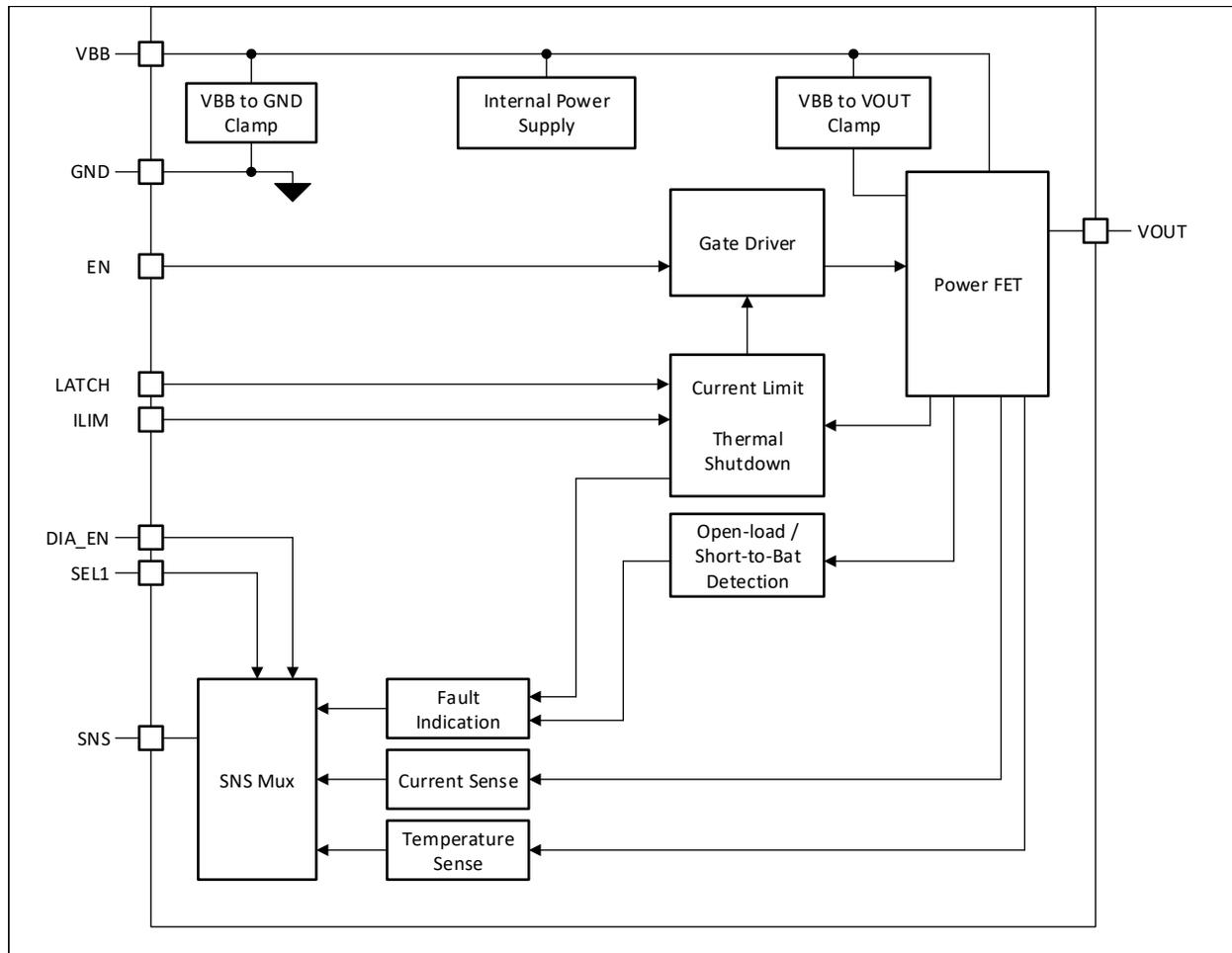
The TPS1HB08-Q1 is one device in a family of TI high side switches. For each device, the part number indicates elements of the device behavior. [图 32](#) gives an example of the device nomenclature.



**图 32. Naming Convention**

## 9.2 Functional Block Diagram

The functional block diagram shown is for device versions A/B. For version F, the ILIM pin will be replaced by open drain output FLT.



## 9.3 Feature Description

### 9.3.1 Protection Mechanisms

The TPS1HB08-Q1 is designed to operate in the automotive environment. The protection mechanisms allow the device to be robust against many system-level events such as load dump, reverse battery, short-to-ground, and more.

There are two protection features which, if triggered, will cause the switch to automatically disable:

- Thermal Shutdown
- Current Limit

When any of these protections are triggered, the device will enter the FAULT state. In the FAULT state, the fault indication will be available on the SNS pin (see the [Diagnostic Mechanisms](#) section of the data sheet for more details). For version F of the device, the fault will also be indicated on the FLT pin.

The switch is no longer held off and the fault indication is reset when all of the below conditions are met:

- LATCH pin is low
- $t_{\text{RETRY}}$  has expired
- All faults are cleared (thermal shutdown, current limit)

## Feature Description (接下页)

### 9.3.1.1 Thermal Shutdown

The TPS1HB08-Q1 includes a temperature sensor on the power FET and also within the controller portion of the device. There are two cases that the device will consider to be a thermal shutdown fault:

- $T_{J,FET} > T_{ABS}$
- $(T_{J,FET} - T_{J,controller}) > T_{REL}$

After the fault is detected, the switch will turn off. If  $T_{J,FET}$  passes  $T_{ABS}$ , the fault is cleared when the switch temperature decreases by the hysteresis value,  $T_{HYS}$ . If instead the  $T_{REL}$  threshold is exceeded, the fault is cleared after  $T_{RETRY}$  passes.

### 9.3.1.2 Current Limit

When  $I_{OUT}$  reaches the current limit threshold,  $I_{CL}$ , the channel will switch off immediately. The  $I_{CL}$  value will vary with slew rate and a fast current increase that occurs during a powered-on short circuit can temporarily go above the specified  $I_{CL}$  value. When the switch is in the FAULT state it will output an output current  $I_{SNSFH}$  on the SNS pin and on version F of the device, the fault will also be indicated on the corresponding FLT pin.

During a short circuit event, the device will hit the  $I_{CL}$  value that is listed in the Electrical Characteristics table (for the given device version and  $R_{ILIM}$ ) and then turn the output off to protect the device. The device will register a short circuit event when the output current exceeds  $I_{CL}$ , however the measured maximum current may exceed the  $I_{CL}$  value due to the TPS1HB08-Q1 deglitch filter and turn-off time. This deglitch time is defined at 3  $\mu$ s so therefore use the test setup described in [TPS1HB08-Q1 AEC-Q100-012 Short Circuit Reliability](#) and take 3  $\mu$ s before the peak value as the  $I_{CL}$ . The device is guaranteed to protect itself during a short circuit event over the nominal supply voltage range (as defined in the Electrical Characteristics table) at 125°C.

On version F of the device, the current limit set point of the device is flat from -40°C to 60°C, and then will linearly decrease until 150°C. This decrease of the current limit is designed to protect the part in even hot temperatures where a short-circuit event causes more damage.

#### 9.3.1.2.1 Current Limit Foldback

Version B and F of the TPS1HB08-Q1 implement a current limit foldback feature that is designed to protect the device in the case of a long-term fault condition. If the device undergoes fault shutdown events (either of thermal shutdown or current limit) seven consecutive times, the current limit will be reduced to half of the original value. The device will revert back to the original current limit threshold if either of the following occurs:

- The device goes to standby mode.
- The switch turns on and turns off without any fault occurring.

Version A do not implement the current limit foldback due to the lower current limit causing less harm during repetitive long-term faults.

#### 9.3.1.2.2 Programmable Current Limit

All versions except F of the TPS1HB08-Q1 include an adjustable current limit. Some applications (for example, incandescent bulbs) will require a high current limit while other applications can benefit from a lower current limit threshold. In general, wherever possible a lower current limit is recommended due to allowing system advantages through:

- Reduced size and cost in current carrying components such as PCB traces and module connectors
- Less disturbance at the power supply ( $V_{BB}$  pin) during a short circuit event
- Improved protection of the downstream load

To set the current limit threshold, connect a resistor from  $I_{LIM}$  to  $V_{BB}$ . The current limit threshold is determined by [Equation 1](#) ( $R_{ILIM}$  in k $\Omega$ ):

$$I_{CL} = K_{CL} / R_{ILIM} \quad (1)$$

The  $R_{ILIM}$  range is between 5 k $\Omega$  and 25 k $\Omega$ . An  $R_{ILIM}$  resistor is required, however in the fault case where the pin is floating, grounded, or outside of this range the current limit will default to an internal level that is defined in the [Specifications](#) section of this document. If  $R_{ILIM}$  is out of this range, the device cannot guarantee complete short-circuit protection.

## Feature Description (接下页)

### 注

Capacitance on the  $I_{LIM}$  pin can cause  $I_{LIM}$  to go out of range during short circuit events. For accurate current limiting, place  $R_{ILIM}$  near to the device with short traces to ensure  $<5$  pF capacitance to GND on the  $I_{LIM}$  pin.

For device version F, there is no  $I_{LIM}$  pin and the current limit is not adjustable. In this case, the device will current limit at the internal threshold  $I_{CL}$  as defined in the [Electrical Characteristics](#) section.

### 9.3.1.2.3 Undervoltage Lockout (UVLO)

The device monitors the supply voltage  $V_{BB}$  to prevent unpredicted behaviors in the event that the supply voltage is too low. When the supply voltage falls down to  $V_{UVLOF}$ , the output stage is shut down automatically. When the supply rises up to  $V_{UVLOR}$ , the device turns back on.

During an initial ramp of  $V_{BB}$  from 0 V at a ramp rate slower than 1 V/ms,  $V_{EN}$  pin will have to be held low until  $V_{BB}$  is above UVLO threshold (with respect to board ground) and the supply voltage to the device has reliably reached above the UVLO condition. For best operation, ensure that  $V_{BB}$  has risen above UVLO before setting the  $V_{EN}$  pin to high.

### 9.3.1.2.4 $V_{BB}$ During Short-to-Ground

When  $V_{OUT}$  is shorted to ground, the module power supply ( $V_{BB}$ ) can have a transient decrease. This is caused by the sudden increase in current flowing through the wiring harness cables. To achieve ideal system behavior, it is recommended that the module maintain  $V_{BB} > 3$  V (above the maximum  $V_{UVLOF}$ ) during  $V_{OUT}$  short-to-ground. This is typically accomplished by placing bulk capacitance on the power supply node.

### 9.3.1.3 Voltage Transients

The TPS1HB08-Q1 device contains two types of voltage clamps which protect the FET against system-level voltage transients. The two different clamps are shown in [图 33](#).

The clamp from  $V_{BB}$  to GND is primarily used to protect the controller from positive transients on the supply line (for example, ISO7637-2). The clamp from  $V_{BB}$  to  $V_{OUT}$  is primarily used to limit the voltage across the FET when switching off an inductive load. If the voltage potential from  $V_{BB}$  to GND exceeds the  $V_{BB}$  clamp level, the clamp will allow current to flow through the device from  $V_{BB}$  to GND (Path 2). If the voltage potential from  $V_{BB}$  to  $V_{OUT}$  exceeds the clamping voltage, the power FET will allow current to flow from  $V_{BB}$  to  $V_{OUT}$  (Path 3). Additional capacitance from  $V_{BB}$  to GND can increase the reliability of the system during ISO 7637 pulse 2 A testing.

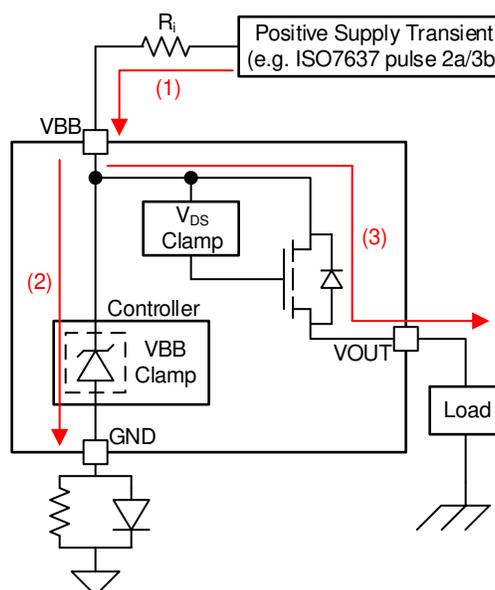


图 33. Current Path During Supply Voltage Transient

## Feature Description (接下页)

### 9.3.1.3.1 Load Dump

The TPS1HB08-Q1 device is tested according to ISO 16750-2:2010(E) suppressed load dump pulse. The device supports up to 40-V load dump transient and will maintain normal operation during the load dump pulse. If the switch is enabled, it will stay enabled and if the switch is disabled, it will stay disabled.

### 9.3.1.3.2 Driving Inductive Loads

When switching off an inductive load, the inductor may impose a negative voltage on the output of the switch. The TPS1HB08-Q1 includes a voltage clamp to limit voltage across the FET. The maximum acceptable load inductance is a function of the device robustness. With a 5 mH load, the device can withstand one pulse of 95 mJ inductive dissipation at 125°C and can withstand 56 mJ of one million inductive repetitive pulses with a 10 Hz repetitive pulse. If the application parameters exceed this device limit, it is necessary to use a protection device like a freewheeling diode to dissipate the energy stored in the inductor.

For more information on driving inductive loads, refer to TI's [How To Drive Inductive, Capacitive, and Lighting Loads With Smart High Side Switches](#) application report.

### 9.3.1.4 Reverse Battery

In the reverse battery condition, the switch will automatically be enabled regardless of the state of EN to prevent excess power dissipation inside the MOSFET body diode. In many applications (for example, resistive loads), the full load current may be present during reverse battery. In order to activate the automatic switch on feature, all NC pins must be grounded to IC ground.

There are two options for blocking reverse current in the system. The first option is to place a blocking device (FET or diode) in series with the battery supply, blocking all current paths. The second option is to place a blocking diode in series with the GND node of the high-side switch. This method will protect the controller portion of the switch (path 2), but it will not prevent current from flowing through the load (path 3). The diode used for the second option may be shared amongst multiple high-side switches.

Path 1 shown in [图 34](#) is blocked inside of the device.

Feature Description (接下页)

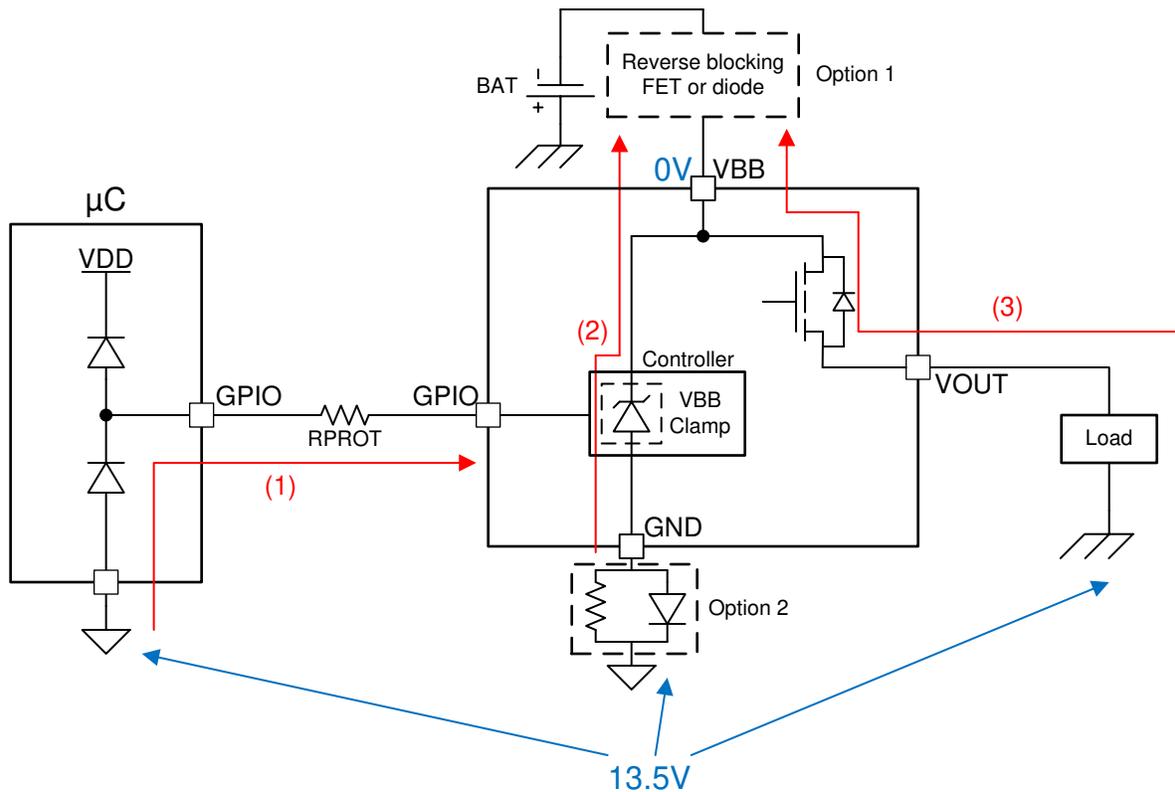


图 34. Current Path During Reverse Battery

For more information on reverse battery protection, refer to TI's [Reverse Battery Protection for High Side Switches](#) application note.

9.3.1.5 Fault Event – Timing Diagrams - Version A and B

注

All timing diagrams assume that the SEL1 pin is low.

The LATCH, DIA\_EN, and EN pins are controlled by the user. The timing diagrams represent a possible use-case.

图 35 shows the immediate current limit switch off behavior. The diagram also illustrates the retry behavior. As shown, the switch will remain latched off until the LATCH pin is low.

Feature Description (接下页)

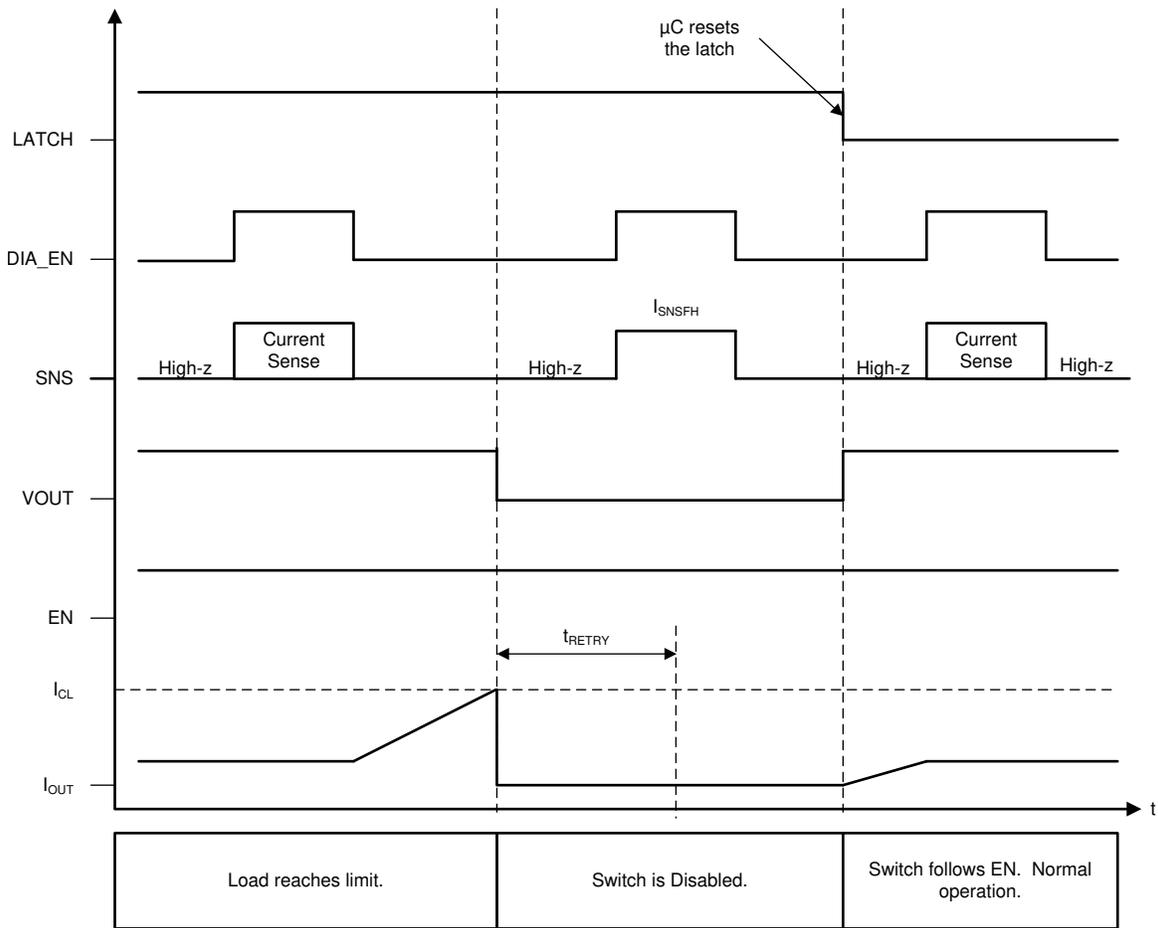
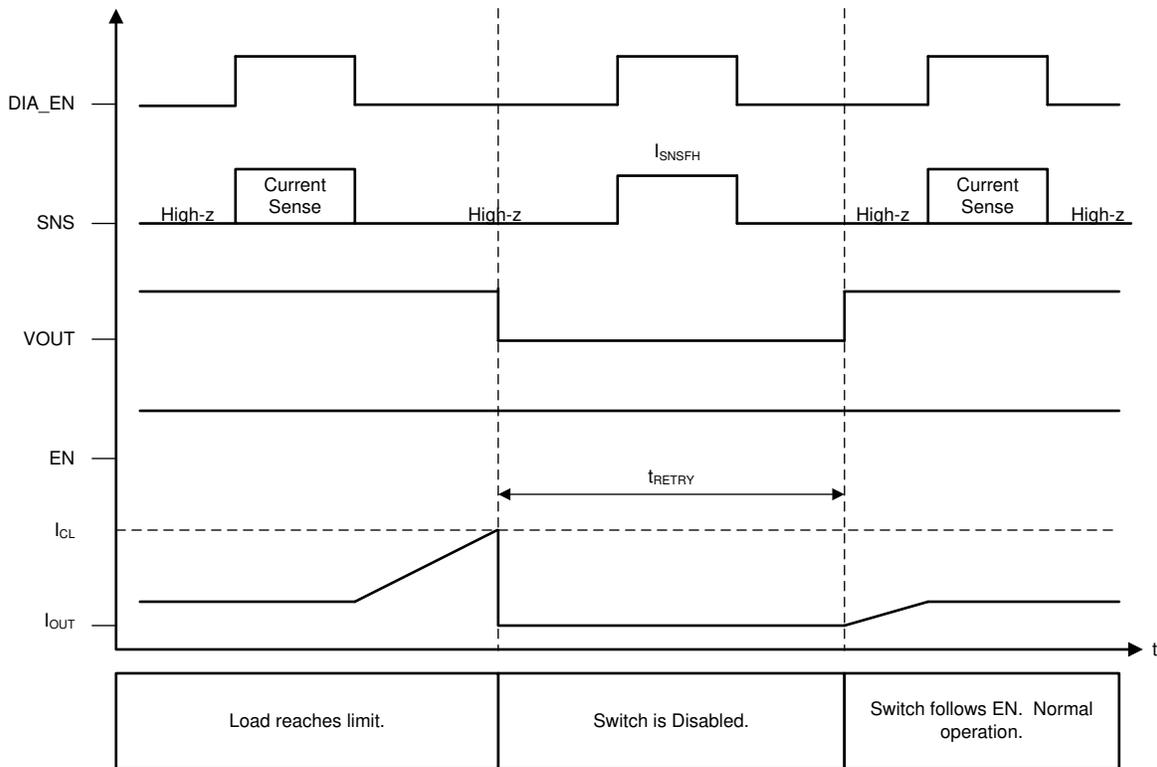


图 35. Current Limit – Version A and B - Latched Behavior

**Feature Description (接下页)**

图 36 shows the immediate current limit switch off behavior. In this example, LATCH is tied to GND; hence, the switch will retry after the fault is cleared and  $t_{RETRY}$  has expired.



**图 36. Current Limit - Version A and B - LATCH = 0**

When the switch retries after a shutdown event, the SNS fault indication will remain until  $V_{OUT}$  has risen to  $V_{BB} - 1.8$  V. Once  $V_{OUT}$  has risen, the SNS fault indication is reset and current sensing is available. If there is a short-to-ground and  $V_{OUT}$  is not able to rise, the SNS fault indication will remain indefinitely. 图 37 illustrates auto-retry behavior and provides a zoomed-in view of the fault indication during retry.

**注**

图 37 assumes that  $t_{RETRY}$  has expired by the time that  $T_J$  reaches the hysteresis threshold.

LATCH = 0 V and DIA\_EN = 5 V

Feature Description (接下页)

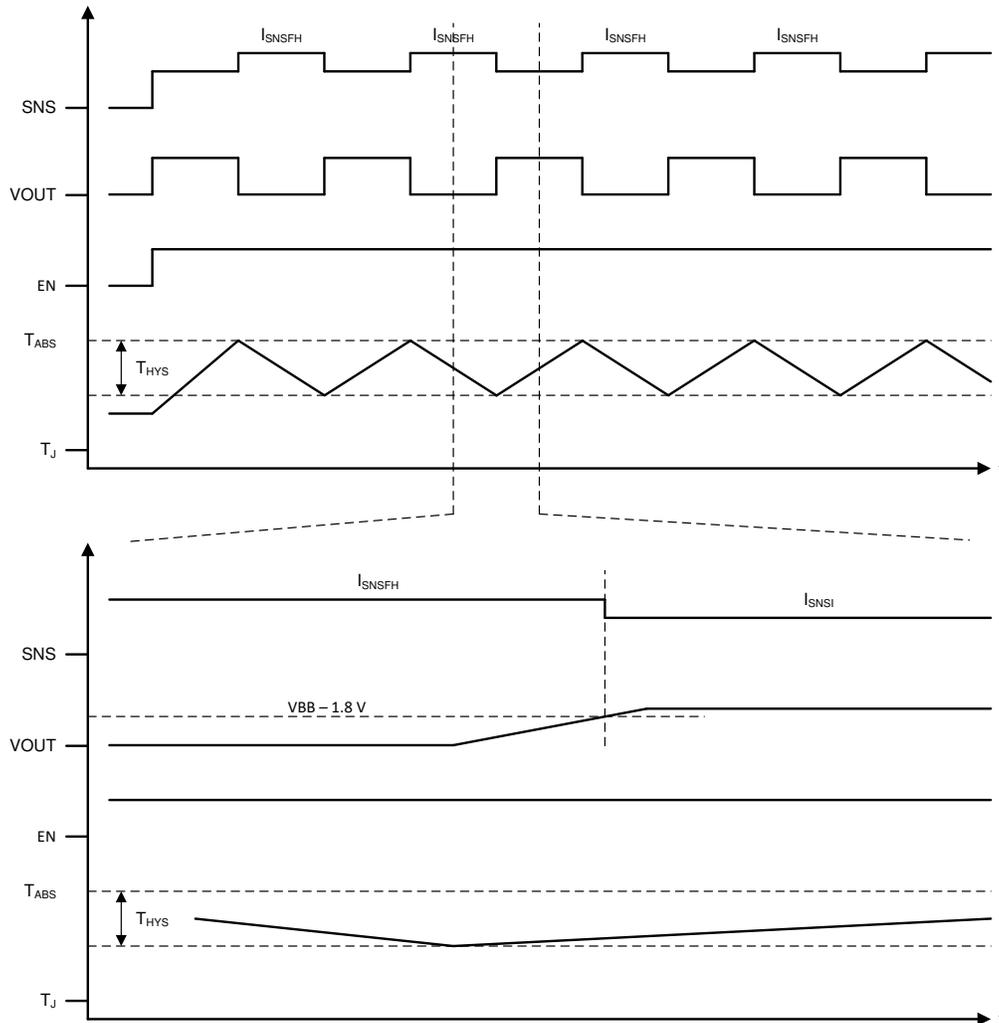


图 37. Fault Indication During Retry

9.3.1.6 Fault Event – Timing Diagrams - Version F

TPS1HB08-Q1 device version F will follow the same timing and fault diagrams as described in [Fault Event – Timing Diagrams - Version A and B](#), with the only difference being the behavior of the FLT pin. For each diagram, if version F is used, it will indicate fault in the same cases as the SNS pin. In every diagram, when the SNS pin outputs  $I_{SNSFH}$ , the FLT pin will go to an open drain state to indicate fault as well.

9.3.2 Diagnostic Mechanisms

9.3.2.1 VOUT Short-to-Battery and Open-Load

The TPS1HB08-Q1 is capable of detecting short-to-battery and open-load events regardless of whether the switch is turned on or off, however the two conditions use different methods.

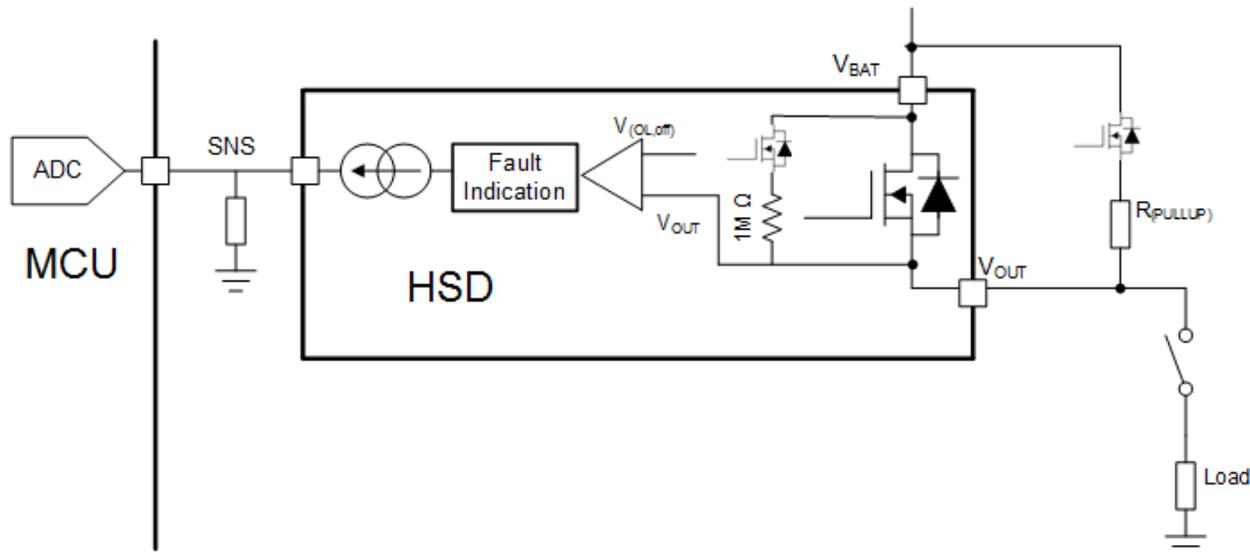
9.3.2.1.1 Detection With Switch Enabled

When the switch is enabled, the VOUT short-to-battery and open-load conditions can be detected by the current sense feature. In both cases, the load current will be measured through the SNS pin as below the expected value.

## Feature Description (接下页)

### 9.3.2.1.2 Detection With Switch Disabled

While the switch is disabled, if DIA\_EN is high, an internal comparator will detect the condition of  $V_{OUT}$ . If the load is disconnected (open load condition) or there is a short to battery the  $V_{OUT}$  voltage will be higher than the open load threshold ( $V_{OL,off}$ ) and a fault is indicated on the SNS pin and the FLT pin on version F. An internal pull-up of  $1\text{ M}\Omega$  is in series with an internal MOSFET switch, so no external component is required if a completely open load must be detected. However, if there is significant leakage or other current draw even when the load is disconnected, a lower value pull-up resistor and switch can be added externally to set the  $V_{OUT}$  voltage above the  $V_{OL,off}$  during open load conditions.



This figure assumes that the device ground and the load ground are at the same potential. In a real system, there may be a ground shift voltage of 1 V to 2 V.

**图 38. Short to Battery and Open Load Detection**

The detection circuitry is only enabled when DIA\_EN = HIGH and EN = LOW. If  $V_{OUT} > V_{OL}$ , the SNS pin will go to the fault level, but if  $V_{OUT} < V_{OL}$  there will be no fault indication. The fault indication will only occur if the SEL1 pin is low.

While the switch is disabled and DIA\_EN is high, the fault indication mechanisms will continuously represent the present status. For example, if  $V_{OUT}$  decreases from greater than  $V_{OL}$  to less than  $V_{OL}$ , the fault indication is reset. Additionally, the fault indication is reset upon the falling edge of DIA\_EN or the rising edge of EN.

Feature Description (接下页)

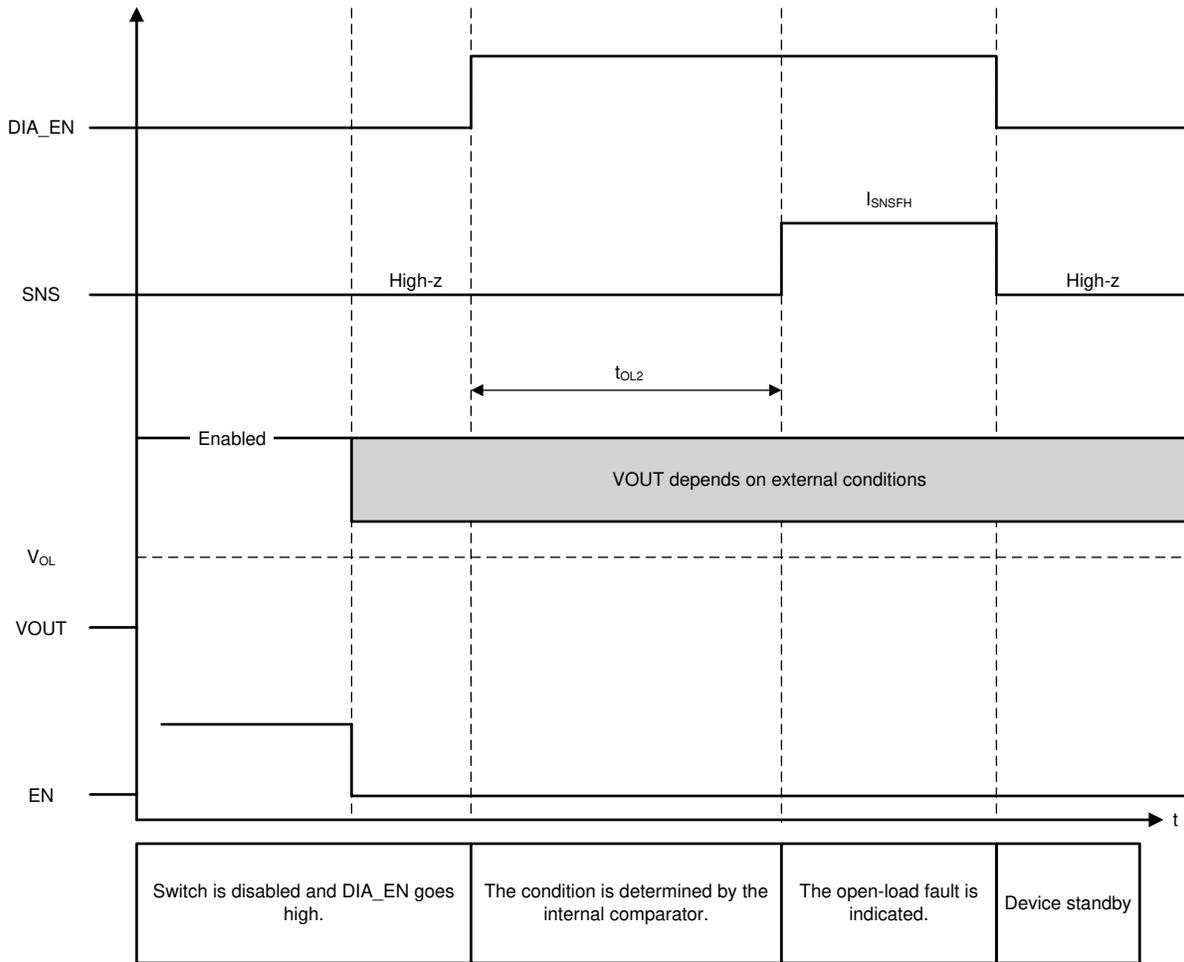


图 39. Open Load

9.3.2.2 SNS Output

The SNS output may be used to sense the load current if the SEL1 pin is low and there is no fault or device temperature if the SEL1 pin is high and there is no fault. The sense circuit will provide a current that is proportional to the selected parameter. This current will be sourced into an external resistor to create a voltage that is proportional to the selected parameter. This voltage may be measured by an ADC or comparator. In addition, the SNS pin can be used to measure the FET temperature.

To ensure accurate sensing measurement, the sensing resistor should be connected to the same ground potential as the  $\mu$ C ADC.

表 3. Analog Sense Transfer Function

PARAMETER	TRANSFER FUNCTION
Load current	$I_{SNSI} = I_{OUT} / K_{SNS} = I_{OUT} / 5000$
Device temperature	$I_{SNST} = (T_J - 25^\circ\text{C}) \times dI_{SNST} / dT + 0.85$

The SNS output will also be used to indicate system faults.  $I_{SNS}$  will go to the predefined level,  $I_{SNSFH}$ , when there is a fault.  $I_{SNSFH}$ ,  $dI_{SNS}/dT$ , and  $K_{SNS}$  are defined in the [Specifications](#) section.

Device version F does not have the capability to measure device temperature, so can only measure load current.

### 9.3.2.2.1 $R_{SNS}$ Value

The following factors should be considered when selecting the  $R_{SNS}$  value:

- Current sense ratio ( $K_{SNS}$ )
- Largest and smallest diagnosable load current required for application operation
- Full-scale voltage of the ADC
- Resolution of the ADC

For an example of selecting  $R_{SNS}$  value, reference  [\$R\_{ILIM}\$  Calculation](#) in the applications section of this datasheet.

#### 9.3.2.2.1.1 High Accuracy Load Current Sense

In many automotive modules, it is required that the high-side switch provide diagnostic information about the downstream load. With more complex loads, high accuracy sensing is required. A few examples follow:

- **LED lighting:** In many architectures, the body control module (BCM) must be compatible with both incandescent bulbs and also LED modules. The bulb may be relatively simple to diagnose. However, the LED module will consume less current and also can include multiple LED strings in parallel. The same BCM is used in both cases, so the high-side switch can accurately diagnose both load types.
- **Solenoid protection:** Often solenoids are precisely controlled by low-side switches. However, in a fault event, the low-side switch cannot disconnect the solenoid from the power supply. A high-side switch can be used to continuously monitor several solenoids. If the system current becomes higher than expected, the high-side switch can disable the module.

#### 9.3.2.2.1.2 SNS Output Filter

To achieve the most accurate current sense value, it is recommended to filter the SNS output. There are two methods of filtering:

- Low-Pass RC filter between the SNS pin and the ADC input. This filter is illustrated in [Figure 43](#) with typical values for the resistor and capacitor. The designer should select a  $C_{SNS}$  capacitor value based on system requirements. A larger value will provide improved filtering but a smaller value will allow for faster transient response.
- The ADC and microcontroller can also be used for filtering. It is recommended that the ADC collects several measurements of the SNS output. The median value of this data set should be considered as the most accurate result. By performing this median calculation, the microcontroller can filter out any noise or outlier data.

#### 9.3.2.3 Fault Indication and SNS Mux

The following faults will be communicated through the SNS output:

- Switch shutdown, due to:
  - Thermal Shutdown
  - Current limit
- Open-Load and  $V_{OUT}$  shorted-to-battery

Open-load and Short-to-battery are not indicated while the switch is enabled, although these conditions can still be detected through the sense current. Hence, if there is a fault indication while the channel is enabled, then it must be either due to an overcurrent or overtemperature event.

The SNS pin will only indicate the fault if the SEL1 pins is low. When the SEL1 pin is high and the device is set to measure temperature, the pin will be measuring the channel FET temperature.

For device version F, the  $\overline{FLT}$  pin will pull low when the device is in any of these fault states.

表 4. Device Version A/B SNS Mux

INPUTS			OUTPUTS
DIA_EN	SEL1	FAULT DETECT <sup>(1)</sup>	SNS
0	X	X	High-z
1	0	0	Output current
1	1	0	Device temperature
1	0	1	I <sub>SNSFH</sub>
1	1	1	Device temperature

For device version F, the SEL1 pin has no functionality so the device cannot output a temperature sense current. In this case, SEL1 should be connected to ground through an R<sub>PROT</sub> resistor and the SNS behavior will follow the table below.

表 5. Device Version F SNS Mux

INPUTS			OUTPUTS	
DIA_EN	SEL1	FAULT DETECT <sup>(1)</sup>	SNS	FLT <sup>(2)</sup>
0	X	X	High-z	High-z
1	X	0	Output current	High-z
1	X	1	I <sub>SNSFH</sub>	Open-drain

9.3.2.4 Resistor Sharing

Multiple high-side devices may use the same SNS resistor as shown in 图 40. This reduces the total number of passive components in the system and the number of ADC terminals that are required of the microcontroller.

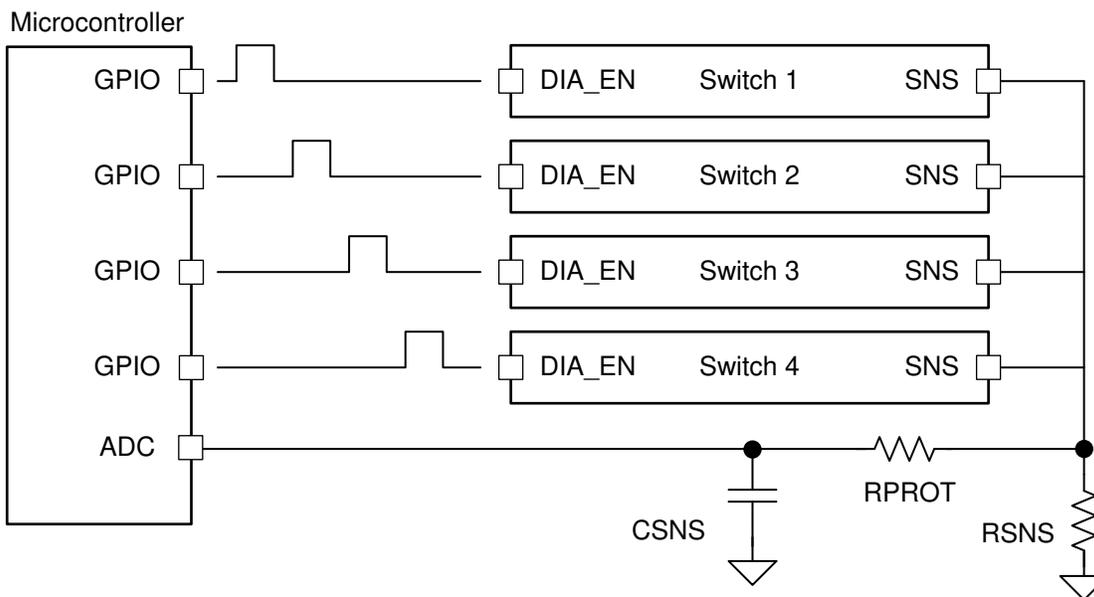


图 40. Sharing R<sub>SNS</sub> Among Multiple Devices

- (1) Fault Detect encompasses multiple conditions:
  - (a) Switch shutdown and waiting for retry
  - (b) Open Load and Short To Battery
- (1) Fault Detect encompasses multiple conditions:
  - (a) Switch shutdown and waiting for retry
  - (b) Open Load / Short To Battery
- (2) Version F Only

### 9.3.2.5 High-Frequency, Low Duty-Cycle Current Sensing

Some applications will operate with a high-frequency, low duty-cycle PWM or require fast settling of the SNS output. For example, a 250 Hz, 5% duty cycle PWM will have an on-time of only 200  $\mu$ s that must be accommodated. The micro-controller ADC may sample the SNS signal after the defined settling time  $t_{\text{SNSION3}}$ .

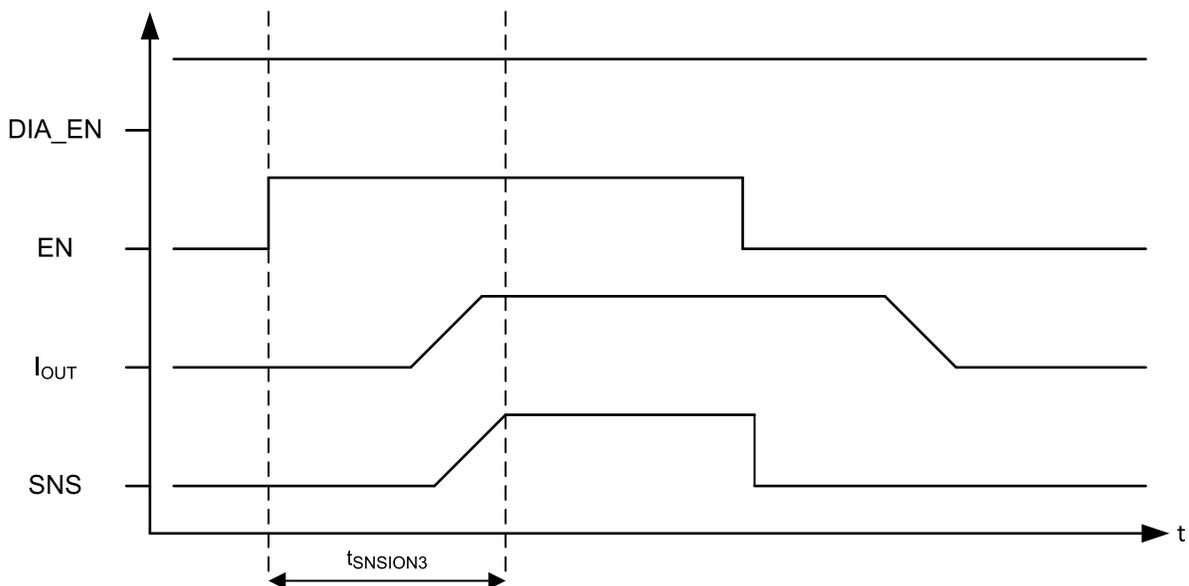


图 41. Current Sensing in Low-Duty Cycle Applications

## 9.4 Device Functional Modes

During typical operation, the TPS1HB08-Q1 can operate in a number of states that are described below and shown as a state diagram in 图 42.

### 9.4.1 Off

Off state occurs when the device is not powered.

### 9.4.2 Standby

Standby state is a low-power mode used to reduce power consumption to the lowest level. Diagnostic capabilities are not available in Standby mode.

### 9.4.3 Diagnostic

Diagnostic state may be used to perform diagnostics while the switch is disabled.

### 9.4.4 Standby Delay

The Standby Delay state is entered when EN and DIA\_EN are low. After  $t_{\text{STBY}}$ , if the EN and DIA\_EN pins are still low, the device will go to Standby State.

### 9.4.5 Active

In Active state, the switch is enabled. The diagnostic functions may be turned on or off during Active state.

Device Functional Modes (接下页)

9.4.6 Fault

The Fault state is entered if a fault shutdown occurs (thermal shutdown or current limit). After all faults are cleared, the LATCH pin is low, and the retry timer has expired, the device will transition out of Fault state. If the EN pin is high, the switch will re-enable. If the EN pin is low, the switch will remain off.

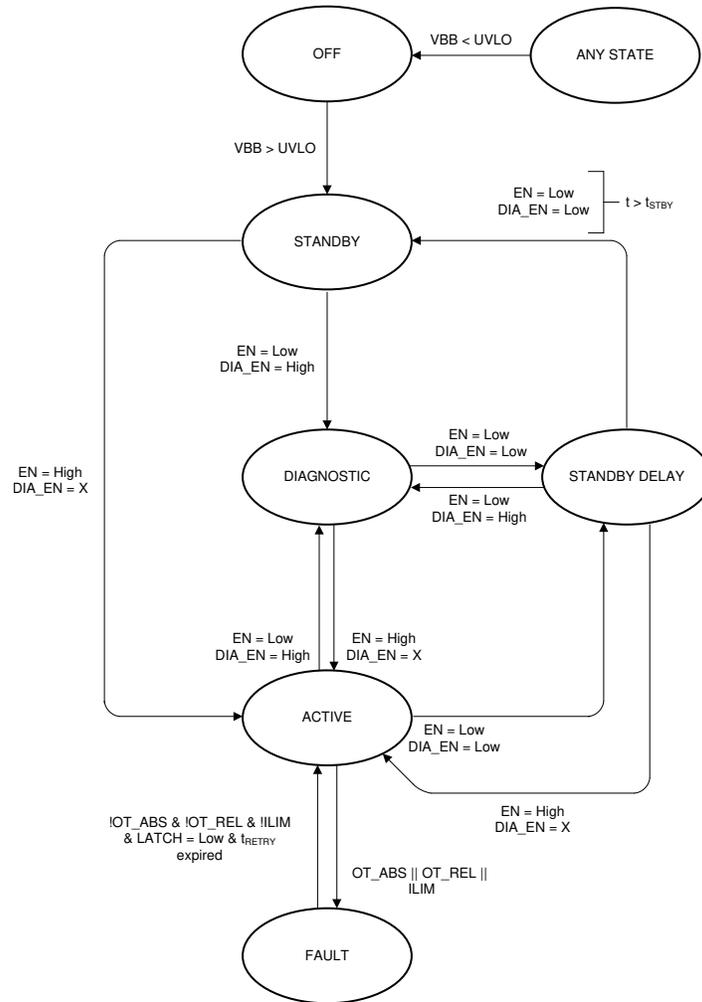


图 42. State Diagram

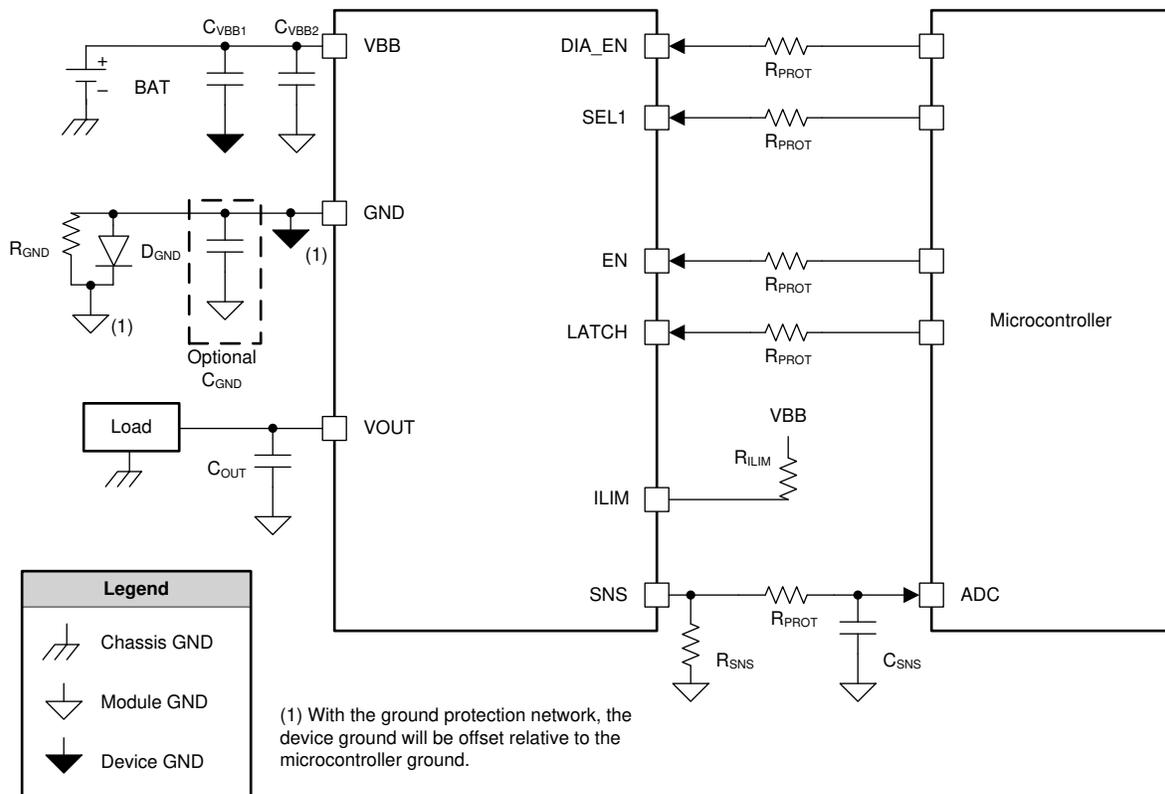
## 10 Application and Implementation

注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

### 10.1 Application Information

图 43 shows the schematic of a typical application for version A or B of the TPS1HB08-Q1. It includes all standard external components. This section of the datasheet discusses the considerations in implementing commonly required application functionality. Version F of the device will replace the ILIM pin with the open drain FLT pin. In this case, the FLT pin must be connected to a 5 V rail through a 10 kΩ pull up resistor.



With the ground protection network, the device ground will be offset relative to the microcontroller ground.

图 43. System Diagram

表 6. Recommended External Components

COMPONENT	TYPICAL VALUE	PURPOSE
R <sub>PROT</sub>	15 kΩ	Protect microcontroller and device I/O pins
R <sub>SNS</sub>	1 kΩ	Translate the sense current into sense voltage
C <sub>SNS</sub>	100 pF - 10 nF	Low-pass filter for the ADC input
R <sub>GND</sub>	4.7 kΩ	Stabilize GND potential during turn-off of inductive load
D <sub>GND</sub>	BAS21 Diode	Protects device during reverse battery
R <sub>ILIM</sub>	5 kΩ - 25 kΩ	Set current limit threshold
C <sub>VBB1</sub>	4.7 nF to Device GND	Filtering of voltage transients (for example, ESD, ISO7637-2) and improved emissions

## Application Information (接下页)

**表 6. Recommended External Components (接下页)**

COMPONENT	TYPICAL VALUE	PURPOSE
C <sub>VBB2</sub>	220 nF to Module GND	Stabilize the input supply and filter out low frequency noise.
C <sub>OUT</sub>	220 nF	Filtering of voltage transients (for example, ESD, ISO7637-2)

### 10.1.1 Ground Protection Network

As discussed in the [Reverse Battery](#) section, D<sub>GND</sub> may be used to prevent excessive reverse current from flowing into the device during a reverse battery event. Additionally, R<sub>GND</sub> is placed in parallel with D<sub>GND</sub> if the switch is used to drive an inductive load. The ground protection network (D<sub>GND</sub> and R<sub>GND</sub>) may be shared amongst multiple high-side switches.

A minimum value for R<sub>GND</sub> may be calculated by using the absolute maximum rating for I<sub>GND</sub>. During the reverse battery condition, I<sub>GND</sub> = V<sub>BB</sub> / R<sub>GND</sub>:

$$R_{GND} \geq V_{BB} / I_{GND}$$

- Set V<sub>BB</sub> = -13.5 V
- Set I<sub>GND</sub> = -50 mA (absolute maximum rating)

$$R_{GND} \geq -13.5 \text{ V} / -50 \text{ mA} = 270 \ \Omega \quad (2)$$

In this example, it is found that R<sub>GND</sub> must be at least 270 Ω. It is also necessary to consider the power dissipation in R<sub>GND</sub> during the reverse battery event:

$$P_{RGND} = V_{BB}^2 / R_{GND} \quad (3)$$

$$P_{RGND} = (13.5 \text{ V})^2 / 270 \ \Omega = 0.675 \text{ W}$$

In practice, R<sub>GND</sub> may not be rated for such a high power. In this case, a larger resistor value should be selected.

### 10.1.2 Interface With Microcontroller

The ground protection network will cause the device ground to be at a higher potential than the module ground (and microcontroller ground). This offset will impact the interface between the device and the microcontroller.

Logic pin voltage will be offset by the forward voltage of the diode. For input pins (for example, EN), the designer must consider the V<sub>IH</sub> specification of the switch and the V<sub>OH</sub> specification of the microcontroller. For a system that *does not* include D<sub>GND</sub>, it is required that V<sub>OH</sub> > V<sub>IH</sub>. For a system that *does* include D<sub>GND</sub>, it is required that V<sub>OH</sub> > (V<sub>IH</sub> + V<sub>F</sub>). V<sub>F</sub> is the forward voltage of D<sub>GND</sub>.

The sense resistor, R<sub>SNS</sub>, should be terminated to the microcontroller ground. In this case, the ADC can accurately measure the SNS signal even if there is an offset between the microcontroller ground and the device ground.

### 10.1.3 I/O Protection

R<sub>PROT</sub> is used to protect the microcontroller I/O pins during system-level voltage transients such as ISO pulses or reverse battery. The SNS pin voltage can exceed the ADC input pin maximum voltage if the fault or saturation current causes a high enough voltage drop across the sense resistor. If that can occur in the design (for example, by switching to a high value R<sub>SNS</sub> to improve ADC input level), then an appropriate external clamp has to be designed to prevent a high voltage at the SNS output and the ADC input.

### 10.1.4 Inverse Current

Inverse current occurs when 0 V < V<sub>BB</sub> < V<sub>OUT</sub>. In this case, current may flow from V<sub>OUT</sub> to V<sub>BB</sub>. Inverse current cannot be caused by a purely resistive load. However, a capacitive or inductive load can cause inverse current. For example, if there is a significant amount of load capacitance and the V<sub>BB</sub> node has a transient droop, V<sub>OUT</sub> may be greater than V<sub>BB</sub>.

The TPS1HB08-Q1 will not detect inverse current. When the switch is enabled, inverse current will pass through the switch. When the switch is disabled, inverse current may pass through the MOSFET body diode. The device will continue operating in the normal manner during an inverse current event.

### 10.1.5 Loss of GND

The ground connection may be lost either on the device level or on the module level. If the ground connection is lost, the switch will be disabled. If the switch was already disabled when the ground connection was lost, the switch will remain disabled. When the ground is reconnected, normal operation will resume.

### 10.1.6 Automotive Standards

The TPS1HB08-Q1 is designed to be protected against all relevant automotive standards to ensure reliable operations when connected to a 12-V automotive battery.

#### 10.1.6.1 ISO7637-2

The TPS1HB08-Q1 is tested according to the ISO7637-2:2011 (E) standard. The test pulses are applied both with the switch enabled and disabled. The test setup includes only the DUT and minimal external components:  $C_{VBB}$ ,  $C_{OUT}$ ,  $D_{GND}$ , and  $R_{GND}$ .

Status II is defined in ISO 7637-1 Function Performance Status Classification (FPSC) as: “The function does not perform as designed during the test but returns automatically to normal operation after the test”. See 表 7 for ISO7637-2:2011 (E) expected results.

表 7. ISO7637-2:2011 (E) Results

TEST PULSE	TEST PULSE SEVERITY LEVEL WITH STATUS II FUNCTIONAL PERFORMANCE		MINIMUM NUMBER OF PULSES OR TEST TIME	BURST CYCLE / PULSE REPETITION TIME	
	LEVEL	US		MIN	MAX
1	III	-112 V	500 pulses	0.5 s	--
2a <sup>(1)</sup>	III	+55 V	500 pulses	0.20	5 s
2b	IV	+10 V	10 pulses	0.5 s	5 s
3a	IV	-220 V	1 hour	90 ms	100 ms
3b	IV	+150 V	1 hour	90 ms	100 ms

(1) 1  $\mu$ F capacitance on  $C_{VBB}$  is required for passing level 3 ISO7637 pulse 2 A.

#### 10.1.6.2 TPS1HB08-Q1 AEC-Q100-012 Short Circuit Reliability

The TPS1HB08-Q1 is tested according to the AEC-Q100-012 Short Circuit Reliability standard. This test is performed to demonstrate the robustness of the device against  $V_{OUT}$  short-to-ground events. Test conditions and test procedures are summarized in . For further details, refer to the AEC-Q100-012 standard document.

Test conditions:

- LATCH = 0 V
- 10 units from 3 separate lots for a total of 30 units.
- $L_{supply} = 5 \mu H$ ,  $R_{supply} = 10 m\Omega$
- $V_{BB} = 14 V$

Test procedure:

- Parametric data is collected on each unit pre-stress
- Each unit is enabled into a short-circuit with the required short circuit cycles or duration as specified
- Functional testing is performed on each unit post-stress to verify that the part still operates as expected

The cold repetitive test is run at 85°C which is the worst case condition for the device to sustain a short circuit. The cold repetitive test refers to the device being given time to cool down between pulses, rather than being run at a cold temperature. The load short circuit is the worst case situation, since the energy stored in the cable inductance can cause additional harm. The fast response of the device ensures current limiting occurs quickly and at a current close to the load short condition. In addition, the hot repetitive test is performed as well.

表 8. AEC-Q100-012 Test Results

TEST	LOCATION OF SHORT	DEVICE VERSION	NO. OF CYCLES / DURATION	NO. OF UNITS	NO. OF FAILS
Cold Repetitive - Long Pulse	Load Short Circuit, $L_{short} = 5 \mu\text{H}$ , $R_{short} = 50 \text{ m}\Omega$ , $T_A = -40^\circ\text{C}$	F	100 k cycles	30	0
Cold Repetitive - Long Pulse - Load Short <sup>(1)</sup>	Load Short Circuit, $L_{short} = 5 \mu\text{H}$ , $R_{short} = 200 \text{ m}\Omega$ , $T_A = 85^\circ\text{C}$	F	100 k cycles	30	0
Cold Repetitive - Long Pulse - Load Short <sup>(1)</sup>	Load Short Circuit, $L_{short} = 5 \mu\text{H}$ , $R_{short} = 200 \text{ m}\Omega$ , $T_A = -40^\circ\text{C}$	F	100 k cycles	30	0
Cold Repetitive - Long Pulse - Terminal Short	Load Short Circuit, $L_{short} < 1 \mu\text{H}$ , $R_{short} < 20 \text{ m}\Omega$ , $T_A = 85^\circ\text{C}$	F	100 k cycles	30	0
Hot Repetitive - Long Pulse	Load Short Circuit, $L_{short} = 5 \mu\text{H}$ , $R_{short} = 100 \text{ m}\Omega$ , $T_A = 25^\circ\text{C}$	F	100 hours	30	0

(1) For Cold Repetitive short, 200 mΩ  $R_{short}$  is used so that the device is at a higher junction temperature before the short circuit event, increasing the harshness of the test.

### 10.1.7 Thermal Information

When outputting current, the TPS1HB08-Q1 will heat up due to the power dissipation. The transient thermal impedance curve can be used to determine the device temperature during a pulse of a given length. This  $Z_{\theta JA}$  value corresponds to a JEDEC standard 2s2p thermal test PCB with thermal vias.

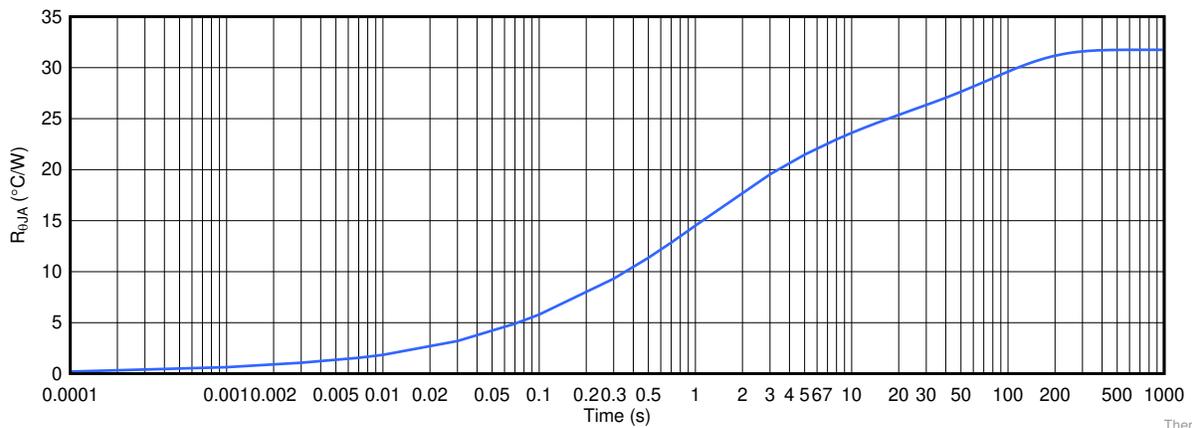
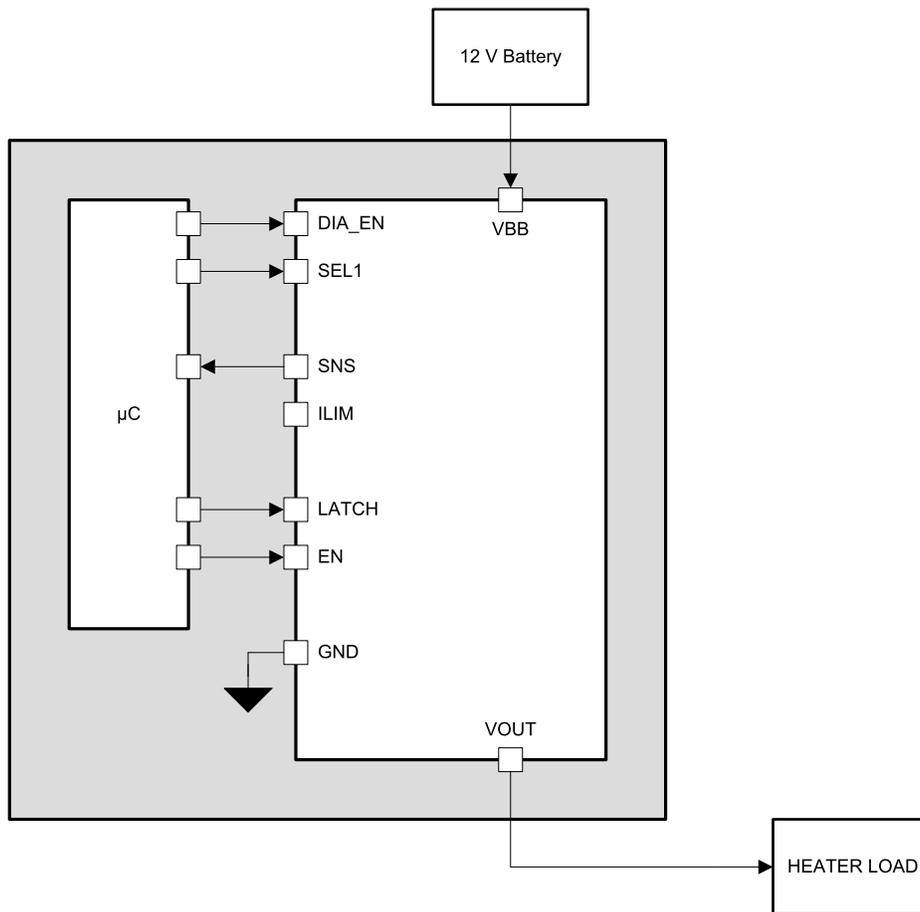


图 44. TPS1HB08-Q1 Transient Thermal Impedance

## 10.2 Typical Application

This application example demonstrates how the TPS1HB08-Q1 device can be used to power resistive heater loads in automotive seats. In this example, we consider a heater load that is powered by the device. This is just one example of the many applications where this device can fit.

**Typical Application (接下页)**

**图 45. Block Diagram for Powering Heater Load**
**10.2.1 Design Requirements**

For this design example, use the input parameters shown in 表 9.

**表 9. Design Parameters**

DESIGN PARAMETER	EXAMPLE VALUE
$V_{BB}$	13.5 V
Load - Heater	130 W max
Load Current Sense	100 mA to 20 A
$I_{LIM}$	12 A
Ambient temperature	70°C
$R_{\theta JA}$	32.6°C/W (depending on PCB)
Device Version	A

**10.2.2 Detailed Design Procedure**
**10.2.2.1 Thermal Considerations**

The 130 W heater load will cause a DC current in the channel under maximum load power condition of around 9.6 A. Therefore, this current at 13.5 V will assume worst case heating.

Power dissipation in the switch is calculated in 公式 4.  $R_{ON}$  is assumed to be 16 mΩ because this is the maximum specification at high temperature. In practice,  $R_{ON}$  will almost always be lower.

$$P_{FET} = I^2 \times R_{ON} \quad (4)$$

$$P_{FET} = (9.6 \text{ A})^2 \times 16 \text{ m}\Omega = 1.47 \text{ W} \quad (5)$$

This means that the maximum FET power dissipation is 1.47 W. The junction temperature of the device can be calculated using [公式 6](#) and the  $R_{\theta JA}$  value from the [Specifications](#) section.

$$T_J = T_A + R_{\theta JA} \times P_{FET} \quad (6)$$

$$T_J = 70^\circ\text{C} + 32.6^\circ\text{C/W} \times 1.47 \text{ W} = 117.9^\circ\text{C}$$

The maximum junction temperature rating for the TPS1HB08-Q1 is  $T_J = 150^\circ\text{C}$ . Based on the above example calculation, the device temperature will stay below the maximum rating even at this high level of current.

### 10.2.2.2 $R_{ILIM}$ Calculation

In this application, the TPS1HB08-Q1 must allow for the maximum DC current with margin but minimize the energy in the switch during a fault condition by minimizing the current limit. For this application, the best  $I_{LIM}$  set point is approximately 12 A. [公式 7](#) allows you to calculate the  $R_{ILIM}$  value that is placed from the  $I_{LIM}$  pins to  $V_{BB}$ .  $R_{ILIM}$  is calculated in  $k\Omega$ .

$$R_{ILIM} = K_{CL} / I_{CL} \quad (7)$$

Because this device is version A, the  $K_{CL}$  value in the [Specifications](#) section is  $160 \text{ A} \times k\Omega$ .

$$R_{ILIM} = 160 (\text{A} \times k\Omega) / 12 \text{ A} = 13.3 \text{ k}\Omega \quad (8)$$

For a  $I_{LIM}$  of 12 A, the  $R_{ILIM}$  value should be set at around 13.3  $k\Omega$

### 10.2.2.3 Diagnostics

If the resistive heating load is disconnected (heater malfunction), an alert is desired. Open-load detection can be performed in the switch-enabled state with the current sense feature of the TPS1HB08-Q1 device. Under open load condition, the current in the SNS pin will be the fault current and the can be detected from the sense voltage measurement.

#### 10.2.2.3.1 Selecting the $R_{ISNS}$ Value

[表 10](#) shows the requirements for the load current sense in this application. The  $K_{SNS}$  value is specified for the device and can be found in the [Specifications](#) section.

**表 10.  $R_{SNS}$  Calculation Parameters**

PARAMETER	EXAMPLE VALUE
Current Sense Ratio ( $K_{SNS}$ )	5000
Largest diagnosable load current	20 A
Smallest diagnosable load current	100 mA
Full-scale ADC voltage	5 V
ADC resolution	10 bit

The load current measurement requirements of 20 A ensures that even in the event of a overcurrent surpassing the set current limit, the MCU can register and react by shutting down the TPS1HB08-Q1, while the low level of 100 mA allows for accurate measurement of low load currents.

The  $R_{SNS}$  resistor value should be selected such that the largest diagnosable load current puts  $V_{SNS}$  at about 95% of the ADC full-scale. With this design, any ADC value above 95% can be considered a fault. Additionally, the  $R_{SNS}$  resistor value should ensure that the smallest diagnosable load current does not cause  $V_{SNS}$  to fall below 1 LSB of the ADC. With the given example values, a 1.2-k $\Omega$  sense resistor satisfies both requirements shown in [表 11](#).

**表 11.  $V_{SNS}$  Calculation**

LOAD (A)	SENSE RATIO	$I_{SNS}$ (mA)	$R_{SNS}$ ( $\Omega$ )	$V_{SNS}$ (V)	% of 5-V ADC
0.1	5000	0.02	1200	0.024	0.5%
20	5000	4	1200	4.800	96.0%

### 10.3 Typical Application

This application example demonstrates how the TPS1HB08-Q1 device can be used to power bulb loads in automotive headlights. In this example, we consider a 65 W bulb that is powered by the device. This is just one example of the many applications where this device can fit.

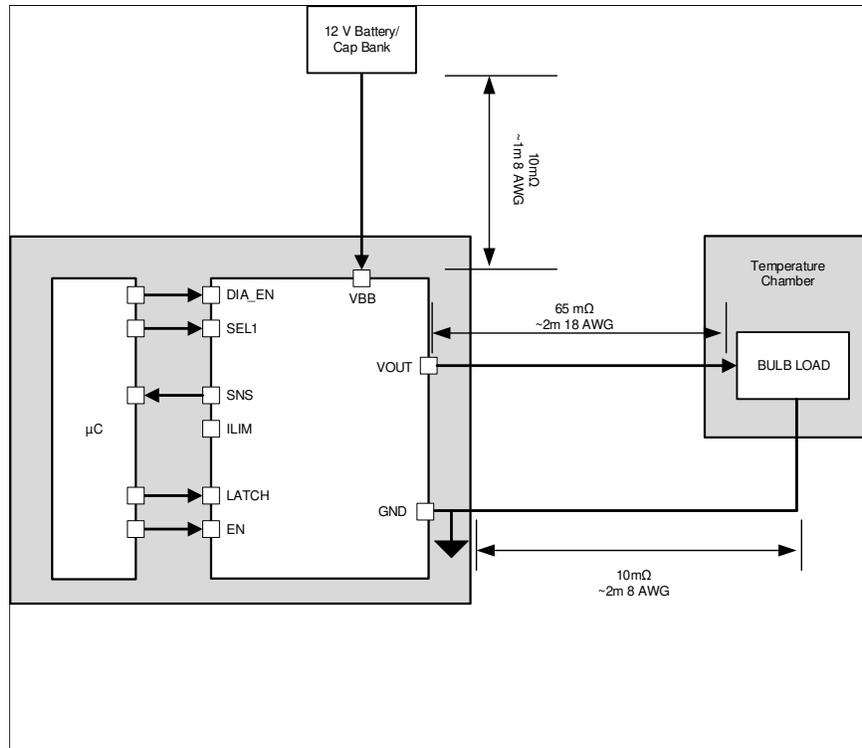


图 46. Block Diagram for Driving Bulb Load

#### 10.3.1 Design Requirements

For this design example, use the input parameters shown in 表 12.

表 12. Design Parameters

DESIGN PARAMETER	EXAMPLE VALUE
$V_{BB}$	16 V
Load - Bulb	65 W W max
Fixed $I_{LIM}$	94 A
Ambient temperature	25°C
Bulb Temperature in Chamber	-40°C
Cable Impedance from Device to Bulb	65 mΩ
Device Version	F

#### 10.3.2 Detailed Design Procedure

The typical bulb test setup is where the device is at 25°C and the bulb is in a temperature chamber at -40°C. The bulb needs to be kept at -40°C so that the impedance is very low and the inrush current will be the highest. The impedance of the cables is important because it will change the inrush current of the bulb as well. The F version of the TPS1HB08-Q1 has a very high fixed current limit so that the inrush current of the bulb can be passed without limitation.

### 10.3.3 Application Curves

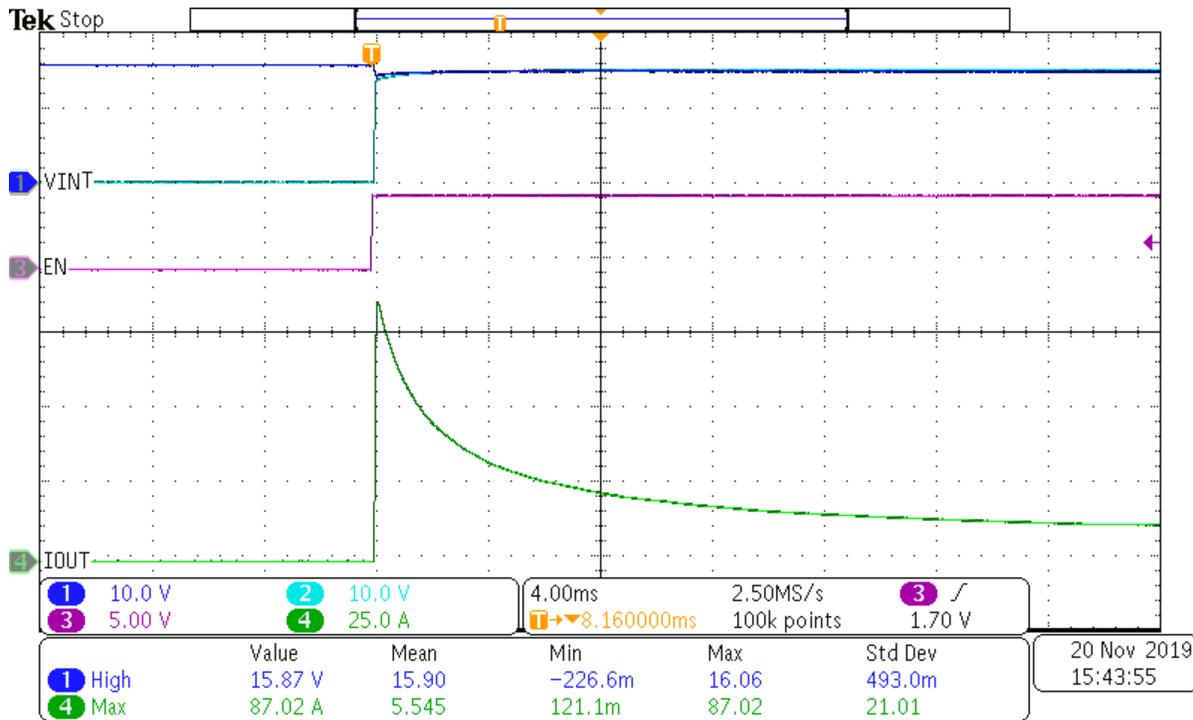


图 47. TPS1HB08-Q1 Version F 65W Bulb Turn On

## 11 Power Supply Recommendations

The TPS1HB08-Q1 device is designed to operate in a 12-V automotive system. The nominal supply voltage range is 6 V to 18 V as measured at the  $V_{BB}$  pin with respect to the GND pin of the device. In this range the device meets full parametric specifications as listed in the [Electrical Characteristics](#) table. The device is also designed to withstand voltage transients beyond this range. When operating outside of the nominal voltage range but within the operating voltage range, the device will exhibit normal functional behavior. However, parametric specifications may not be specified outside the nominal supply voltage range.

表 13. Operating Voltage Range

$V_{BB}$ Voltage Range	Note
3 V to 6 V	Transients such as cold crank and start-stop, functional operation are specified but some parametric specifications may not apply. The device is completely short-circuit protected up to 125°C
6 V to 18 V	Nominal supply voltage, all parametric specifications apply. The device is completely short-circuit protected up to 125°C
18 V to 40 V	Transients such as jump-start and load-dump, functional operation specified but some parametric specifications may not apply

## 12 Layout

### 12.1 Layout Guidelines

To achieve optimal thermal performance, connect the exposed pad to a large copper pour. On the top PCB layer, the pour may extend beyond the package dimensions as shown in the example below. In addition to this, it is recommended to also have a  $V_{BB}$  plane either on one of the internal PCB layers or on the bottom layer.

Vias should connect this plane to the top  $V_{BB}$  pour.

Ensure that all external components are placed close to the pins. Device current limiting performance can be harmed if the  $R_{ILIM}$  is far from the pins and extra parasitics are introduced.

### 12.2 Layout Example

The layout example is for device versions A/B. For device version F, the ILIM pin will be replaced by the  $\overline{FLT}$  pin.

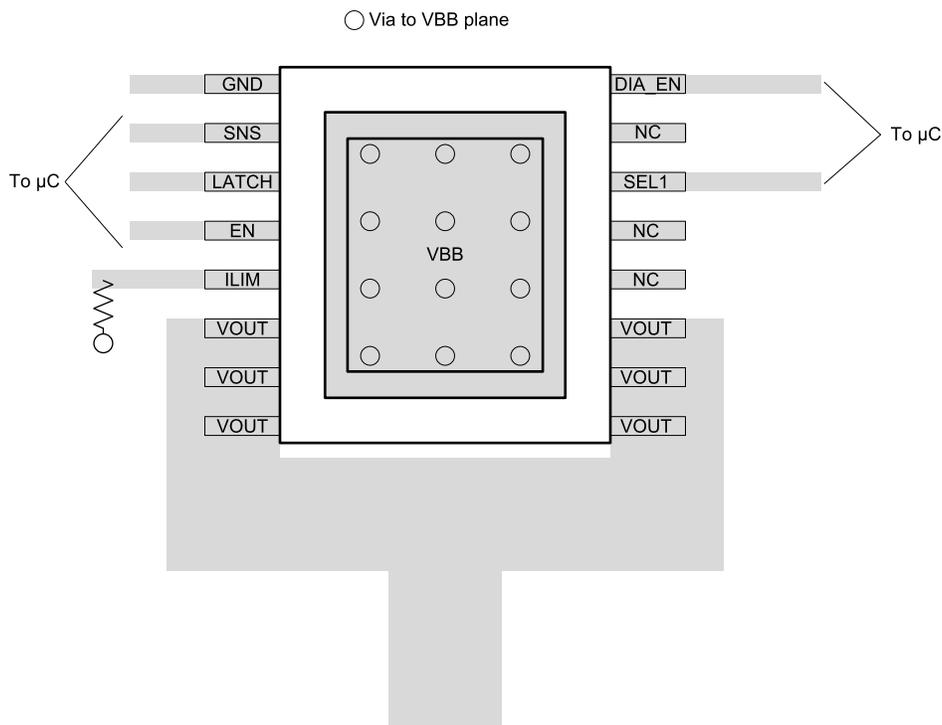


图 48. 16-PWP Layout Example

## 13 器件和文档支持

### 13.1 文档支持

#### 13.1.1 相关文档

请参阅如下相关文档：

- TI 《如何利用智能高侧开关驱动电感、电容和照明负载》
- TI 《智能电源开关的短路可靠性测试》
- TI 《适用于高侧开关的反向电池保护》
- TI 《智能电源开关的可调电流限制》

### 13.2 接收文档更新通知

要接收文档更新通知，请导航至 [ti.com.cn](http://ti.com.cn) 上的器件产品文件夹。单击右上角的通知我进行注册，即可每周接收产品信息更改摘要。有关更改的详细信息，请查看任何已修订文档中包含的修订历史记录。

### 13.3 支持资源

[TI E2E™ support forums](#) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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ESD 的损坏小至导致微小的性能降级，大至整个器件故障。精密的集成电路可能更容易受到损坏，这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

### 13.6 Glossary

[SLYZ022](#) — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

## 14 机械、封装和可订购信息

以下页面包含机械、封装和可订购信息。这些信息是指定器件的最新可用数据。数据如有变更，恕不另行通知，且不会对此文档进行修订。如需获取此数据表的浏览器版本，请查阅左侧的导航栏。

## PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package   Pins	Package qty   Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
<a href="#">TPS1HB08AQPWPRQ1</a>	Active	Production	HTSSOP (PWP)   16	3000   LARGE T&R	ROHS Exempt	NIPDAU	Level-3-260C-168HRS	-40 to 125	1HB08A
TPS1HB08AQPWPRQ1.A	Active	Production	HTSSOP (PWP)   16	3000   LARGE T&R	ROHS Exempt	NIPDAU	Level-3-260C-168HRS	-40 to 125	1HB08A
<a href="#">TPS1HB08BQPWPRQ1</a>	Active	Production	HTSSOP (PWP)   16	3000   LARGE T&R	ROHS Exempt	NIPDAU	Level-3-260C-168HRS	-40 to 125	1HB08B
TPS1HB08BQPWPRQ1.A	Active	Production	HTSSOP (PWP)   16	3000   LARGE T&R	ROHS Exempt	NIPDAU	Level-3-260C-168HRS	-40 to 125	1HB08B
<a href="#">TPS1HB08FQPWPRQ1</a>	Active	Production	HTSSOP (PWP)   16	3000   LARGE T&R	ROHS Exempt	NIPDAU	Level-3-260C-168HRS	-40 to 125	1HB08F
TPS1HB08FQPWPRQ1.A	Active	Production	HTSSOP (PWP)   16	3000   LARGE T&R	ROHS Exempt	NIPDAU	Level-3-260C-168HRS	-40 to 125	1HB08F

(1) **Status:** For more details on status, see our [product life cycle](#).

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

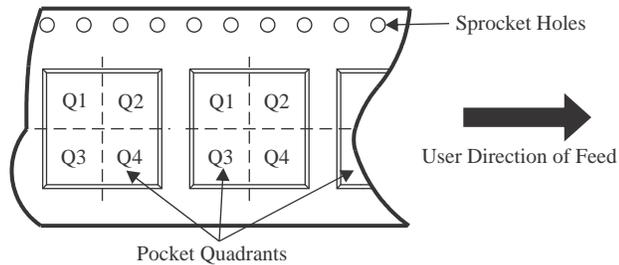
Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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**TAPE AND REEL INFORMATION**

**QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**


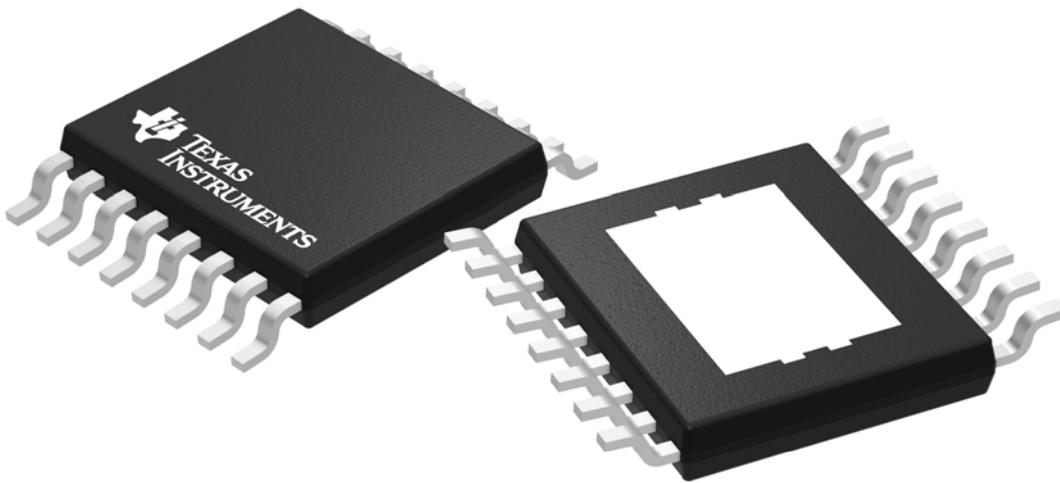
\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS1HB08AQPWRQ1	HTSSOP	PWP	16	3000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TPS1HB08BQPWRQ1	HTSSOP	PWP	16	3000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TPS1HB08FQPWRQ1	HTSSOP	PWP	16	3000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TPS1HB08FQPWRQ1	HTSSOP	PWP	16	3000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

**TAPE AND REEL BOX DIMENSIONS**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPS1HB08AQPWRQ1	HTSSOP	PWP	16	3000	350.0	350.0	43.0
TPS1HB08BQPWRQ1	HTSSOP	PWP	16	3000	350.0	350.0	43.0
TPS1HB08FQPWRQ1	HTSSOP	PWP	16	3000	367.0	367.0	38.0
TPS1HB08FQPWRQ1	HTSSOP	PWP	16	3000	350.0	350.0	43.0



Images above are just a representation of the package family, actual package may vary.  
Refer to the product data sheet for package details.

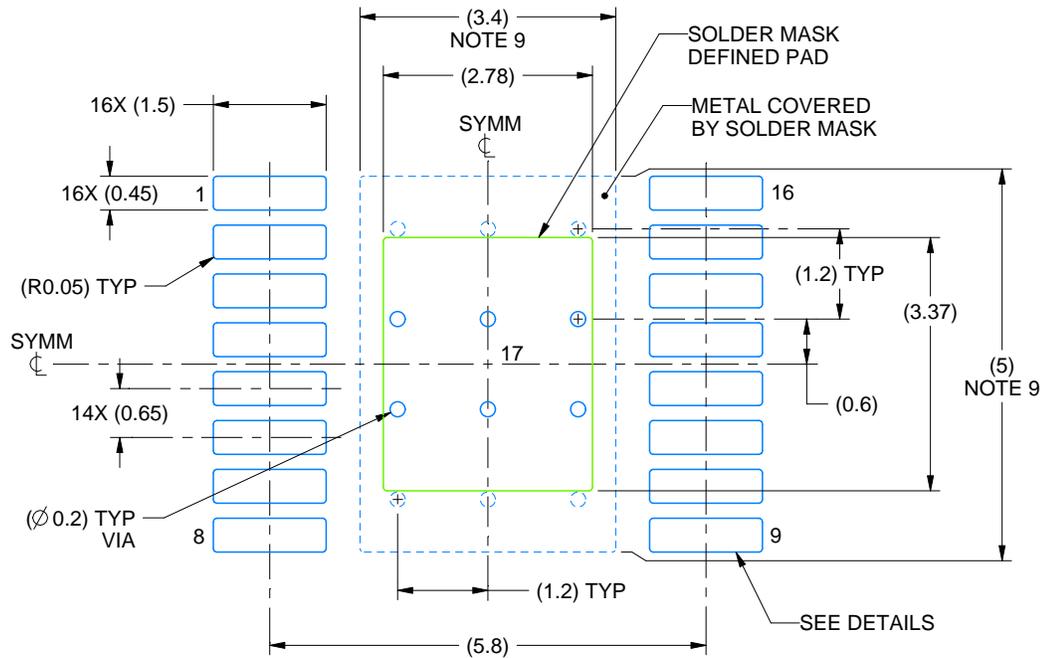


# EXAMPLE BOARD LAYOUT

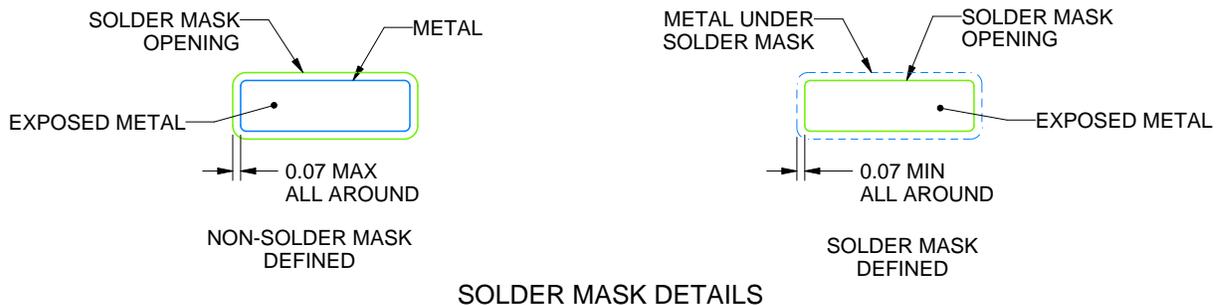
PWP0016M

PowerPAD™ TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



LAND PATTERN EXAMPLE  
EXPOSED METAL SHOWN  
SCALE: 10X



SOLDER MASK DETAILS

4223886/B 09/2019

NOTES: (continued)

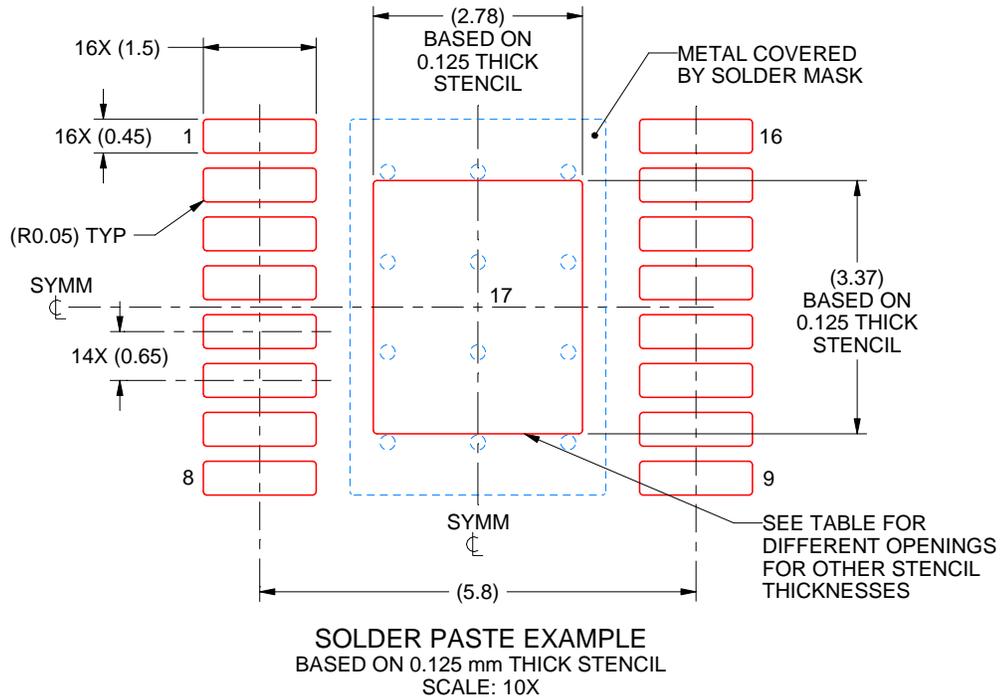
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
8. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature numbers SLMA002 ([www.ti.com/lit/slma002](http://www.ti.com/lit/slma002)) and SLMA004 ([www.ti.com/lit/slma004](http://www.ti.com/lit/slma004)).
9. Size of metal pad may vary due to creepage requirement.
10. Vias are optional depending on application, refer to device data sheet. It is recommended that vias under paste be filled, plugged or tented.

# EXAMPLE STENCIL DESIGN

PWP0016M

PowerPAD™ TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



STENCIL THICKNESS	SOLDER STENCIL OPENING
0.1	3.11 X 3.77
0.125	2.78 X 3.37 (SHOWN)
0.15	2.54 X 3.08
0.175	2.35 X 2.85

4223886/B 09/2019

NOTES: (continued)

11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
12. Board assembly site may have different recommendations for stencil design.

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